

Elastic instabilities in silicon-germanium films

Thomas Frisch, Jean-Noël Aqua
IM2NP, CNRS, Marseille

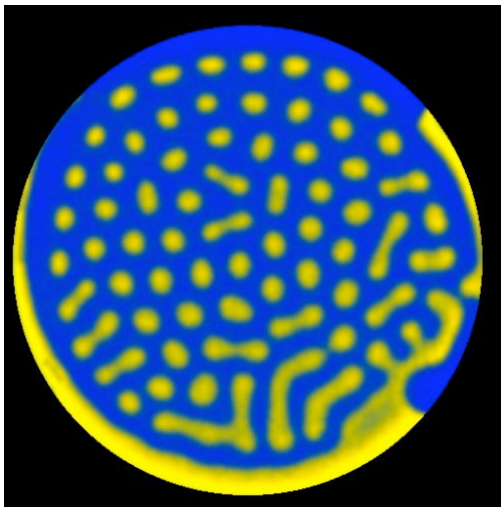


CSCAMM, College Park
October 25, 2010

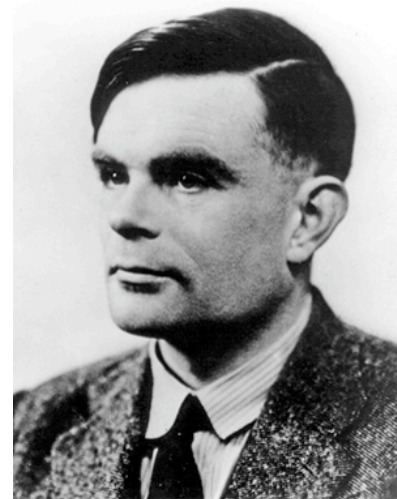
Introduction

Pattern forming instabilities are ubiquitous in non-equilibrium dissipative system: three classical examples

Turing Structures



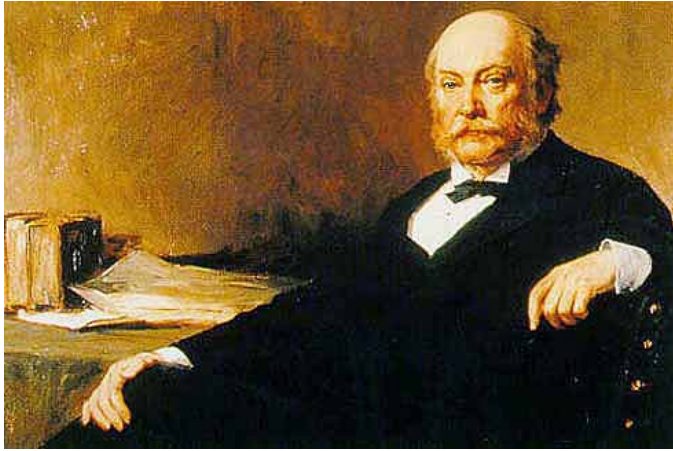
Chemical Turing patterns
Judit Horváth, István Szalai,
Patrick De Kepper, *Science*, 8
Mai 2009.



Alan Turing



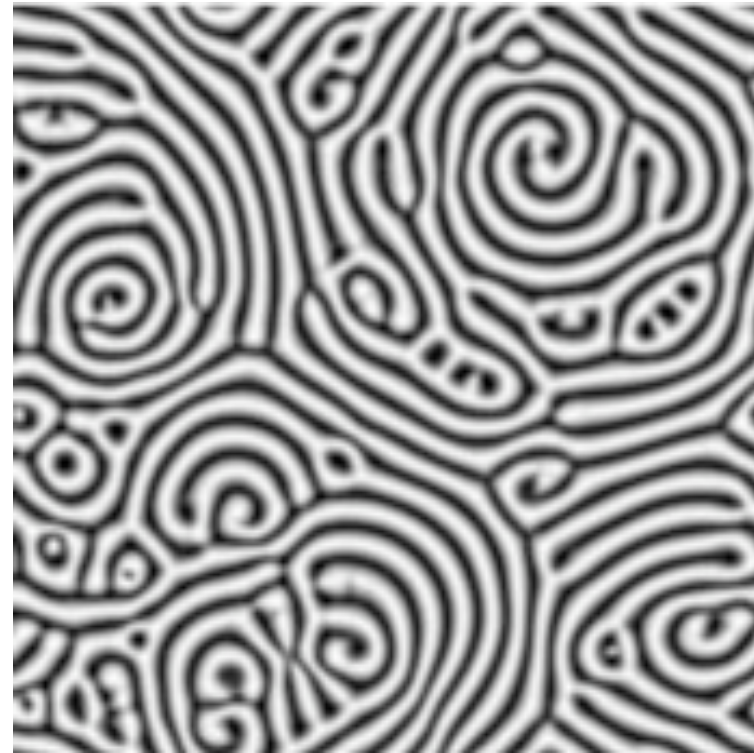
Hydrodynamics convection



Lord Rayleigh

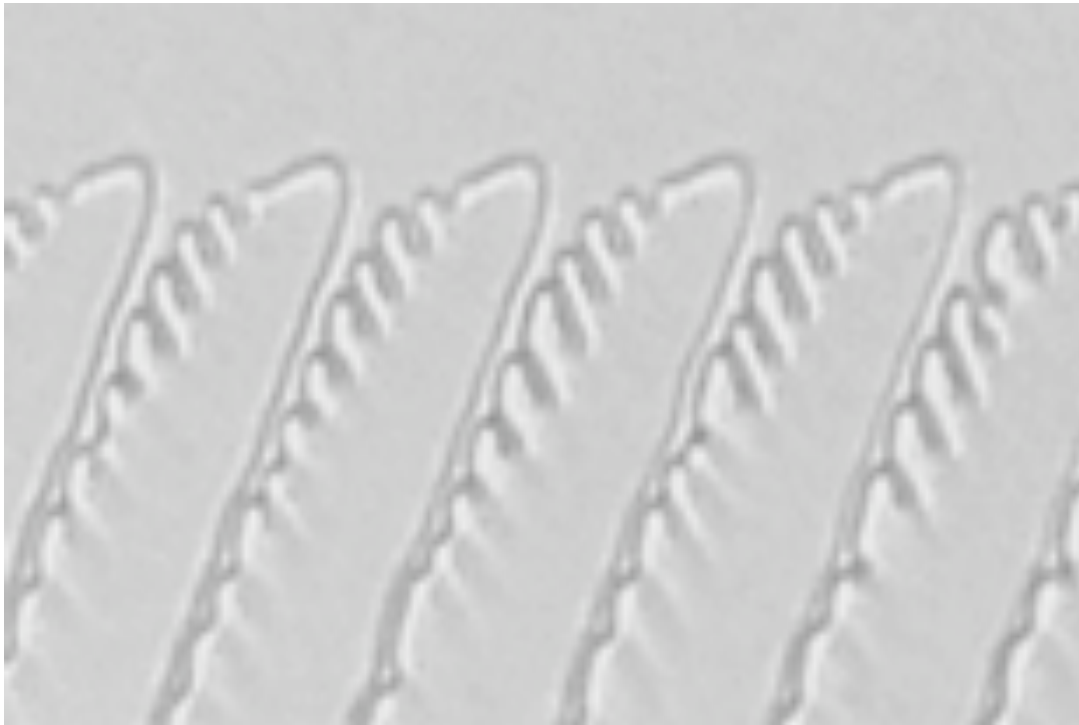


Bénard



Assenheimer and Steinberg , PRL, 1993

Mullins-Sekerka instability



**Dendritic growth, directional solidification,
solid-liquid transition, Pocheau**

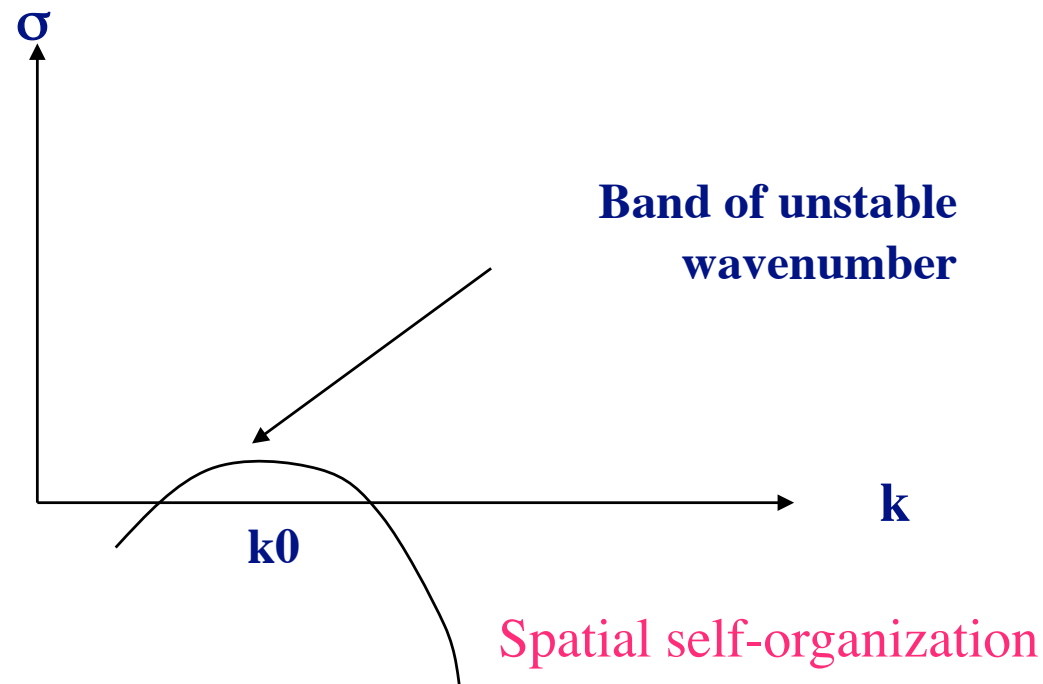


W. Mullins

Common denominator:

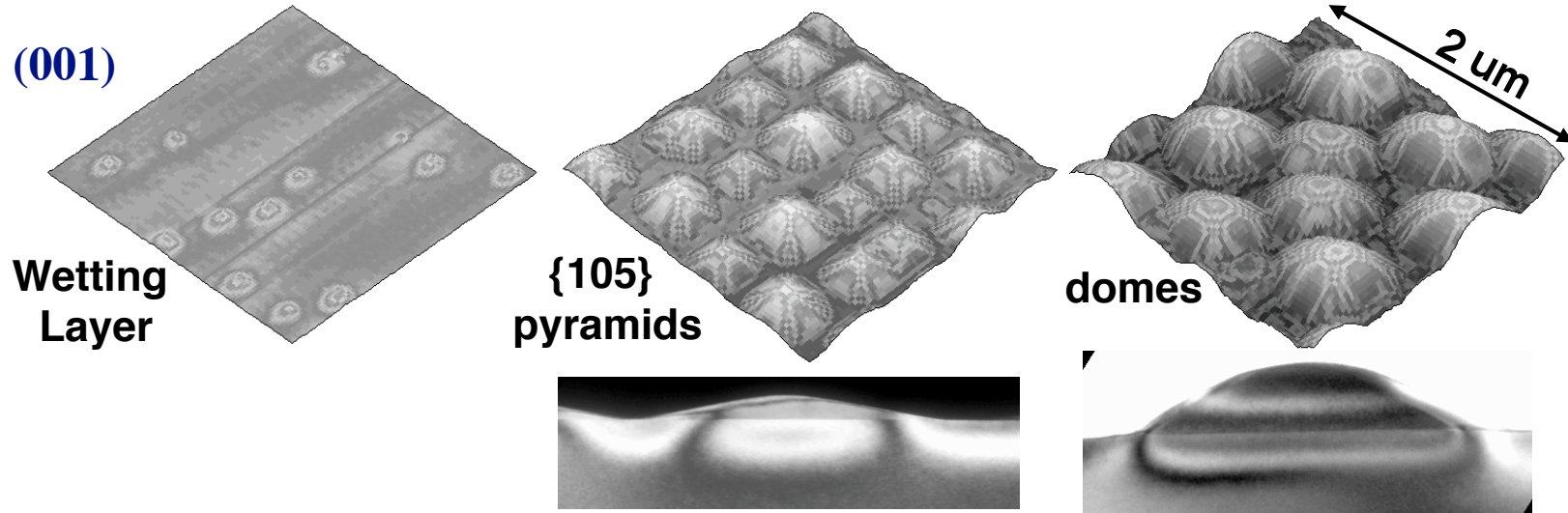
- Finite wavelength instabilities, such that there exists a range of unstable wave numbers

$$\text{Exp} (s t) \text{Exp} (I k x)$$



Motivation: $\text{Ge}_x\text{Si}_{1-x}/\text{Si}$ (001) Coherent Islands: instability regime

$\text{Ge}_{0.2}\text{Si}_{0.8}/\text{Si}$ (001)
750°C



Floro et al, PRL 79, 3946 (1997)

Spencer, Voorhees, Davis and Mac Fadden, PRL, 1991

Spencer, Voorhees, Davis, PRB, 1993

Spencer, Voorhees, Tersoff, 2001

Tromp

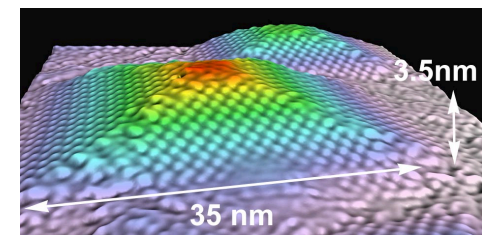
**Lagally,
PRL 2000**

**Stangl et al,
RMP, 2004**

Ge/Si (001), 600°C

Nucleation regime

G. Medeiros-Ribiero, et al.,
Science 279, 353 (1998).



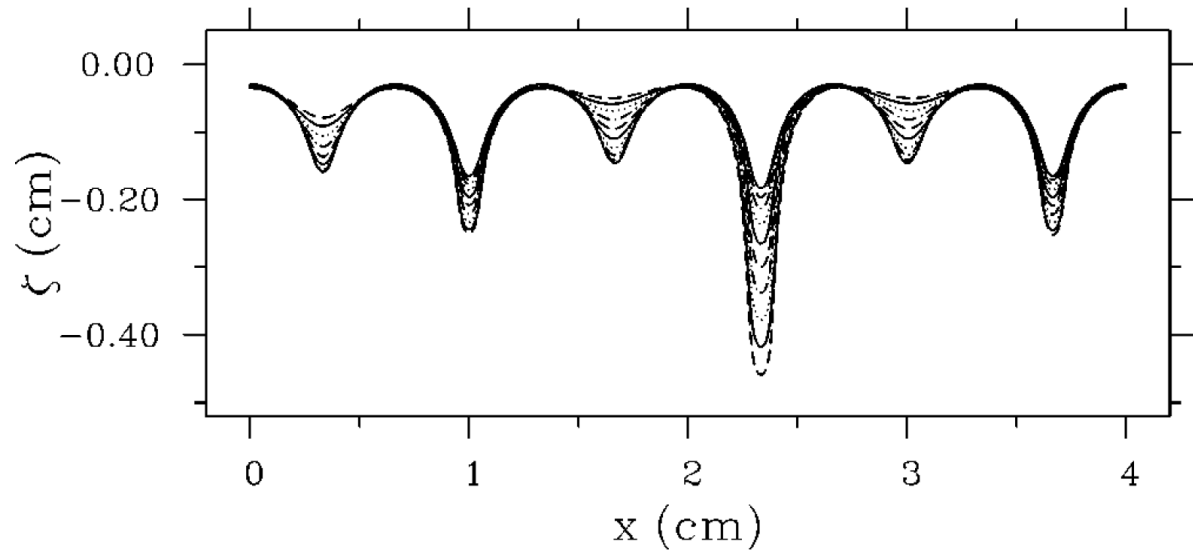
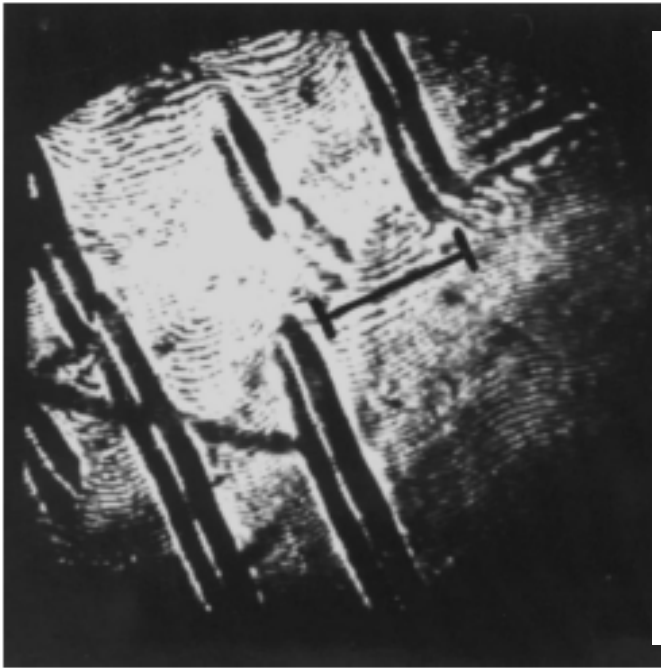
Questions

- What is the coarsening dynamics?
- What is the influence of the anisotropy of surface energy ?
- What is the influence of the film height?

Outline

- Asaro-Tiller-Grinfeld Instability
- The Mullins model for hetero-epitaxy
- Isotropic Case (Non interrupted Coarsening)
- Anisotropic Case (Interrupted Coarsening)
- MBE experiments during annealing
- Conclusion and Perspectives

Grinfeld-instability of liquid-solid helium



Bodensohn 1986, Balibar 1991

Balibar 2005 RMP

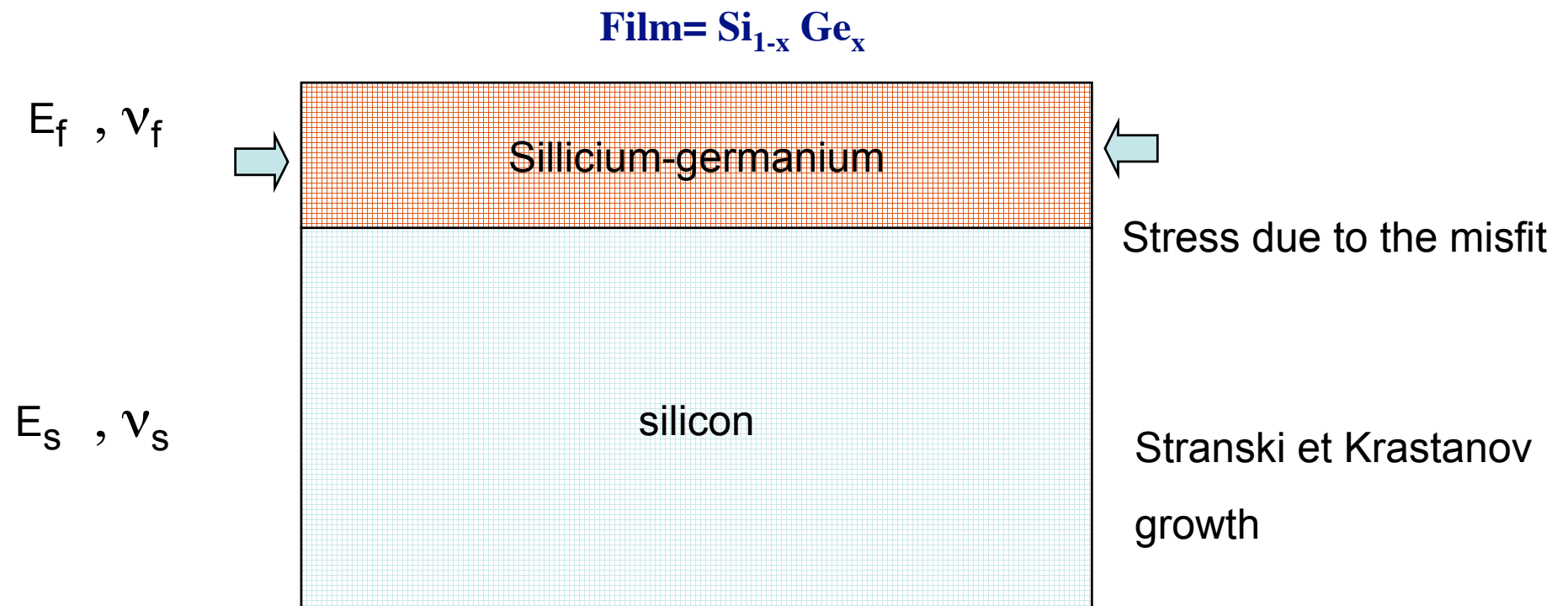
Kassner, Misbah et al, 2001, Phys Rev E,

Phase field methods

The Asaro-Tiller-Grinfeld Instability: morphological instability of a stressed crystal

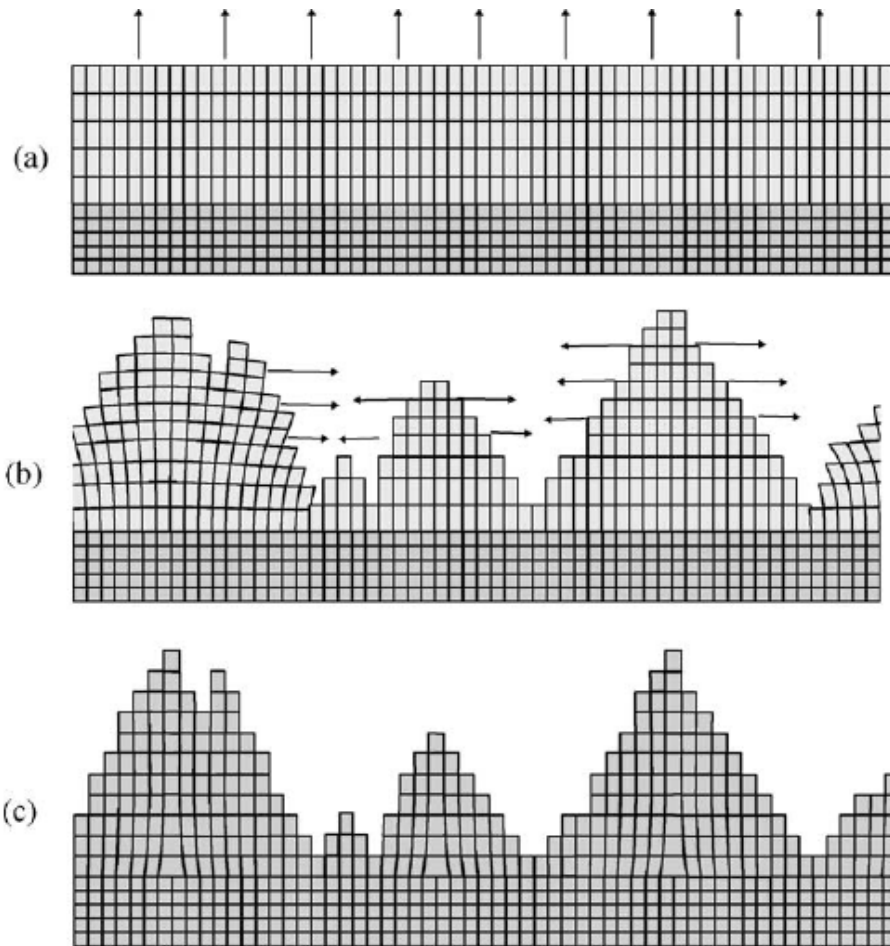
Germanium atoms are larger than silicon atoms

No cracks or dislocations for small misfit



MISFIT $\delta a/a$ of the order of 4.2%

Heteroepitaxy : paradigm Si/Ge systems



Stransky-Krastanov mode of growth.

During **annealing**, islands, separated by a wetting layer, **form and coarsen**. dominated by surface diffusion

$$\mathbf{a}=\mathbf{a}_f, \delta\mathbf{a}=\mathbf{a}_{\text{film}}-\mathbf{a}_{\text{substrate}}$$

$$\text{Vegard Law: } \mathbf{a}_{\text{film}} = x \mathbf{a}_{\text{ge}} + (1-x) \mathbf{a}_{\text{si}}$$

$$l_0 = \frac{\gamma}{E \left(\frac{\delta a}{a} \right)^2}$$

$$t_0 = l_0^4 / (D\gamma)$$

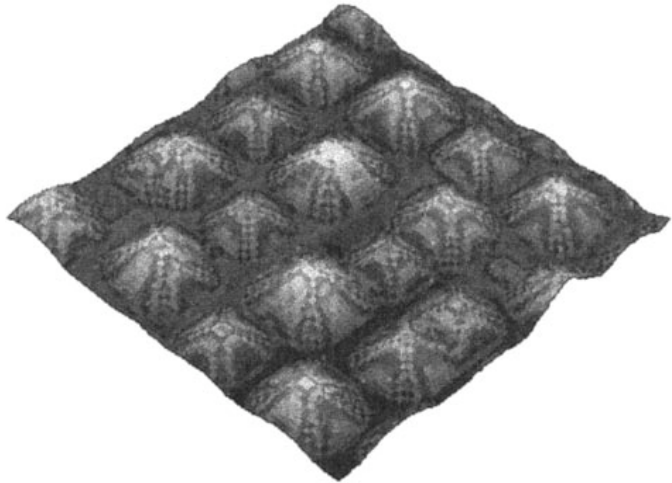
Pimpinelli, Villain « Physics of crystal growth », 1998

Stangl et al, Review of Modern Physics 2004

C. Misbah, O. Pierre-Louis and Y.Saito, Review of Modern Physics, 2010

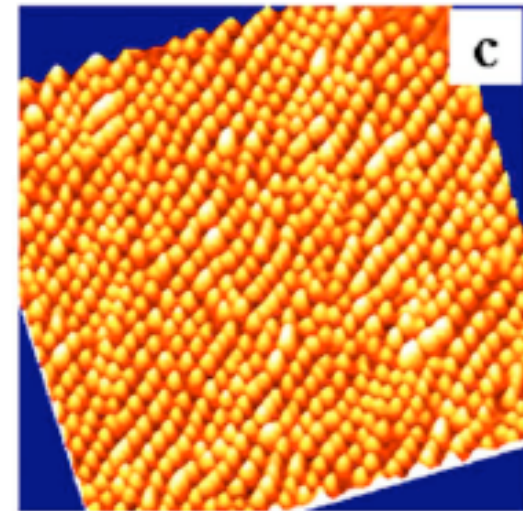
Heteroepitaxy, Si/Ge (IV/IV) or group III/V InGaAs/GaAs

Elastic instability: island formation is ubiquitous



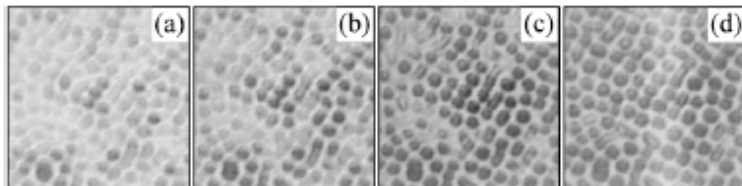
$$l_0^{-1} = \frac{E}{\gamma} \left(\frac{\delta a}{a} \right)^2$$

$$t_0 = l_0^4 / (D\gamma)$$



Floro **et al**, PRB
99

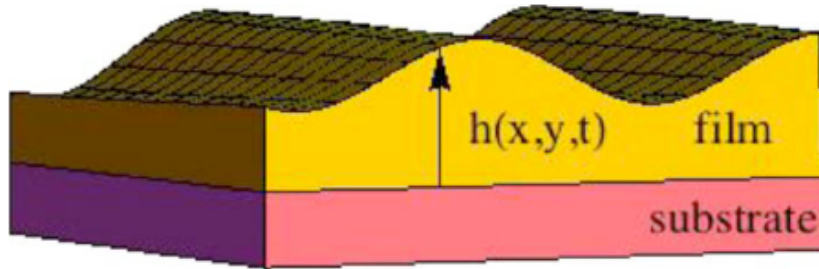
Nucleationless formation of islands in
heteroepitaxy from surface ripples.



Berbezier, Ronda, PRB 2007,
vicinal surface SI (001)

Sutter **et al**. PRL 2000

The « Mullins » surface diffusion model



No alloying, no volume diffusion

$$\frac{\partial h}{\partial t} + \nabla \cdot \mathbf{J} = 0$$

$$\mathbf{J} = -D \nabla \mu$$

Elastic energy

Surface energy

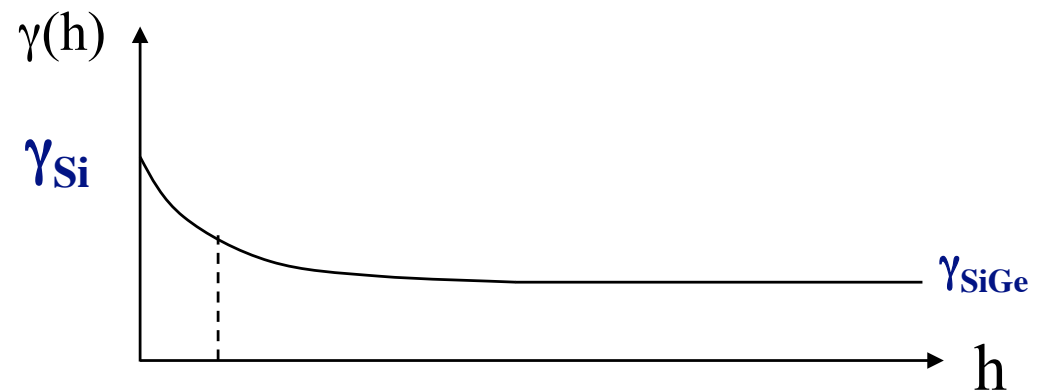
Wetting potential

$$\mu = \mathcal{E}[h] + \gamma(h) \kappa(h) + \gamma'(h) / \sqrt{1 + |\nabla h|^2},$$

$\kappa(\mathbf{h})$ is the curvature

Wetting potential model

$$\gamma(h) = \gamma [1 + c_w \exp(-h/\delta)]$$



δ is a few layers, ~ 2 nm

Chiu, Gao, 1993,
Muller and Kern,
F. Liu

Spencer, Tekalign, Golovin,
Davis, Voorhess, PRB, 2003

Levine et al, Phys Rev B, 2007

Aqua et al, Phys Rev B, 2007

Film and substrate elasticity

Elastic energy

$$\partial_j \sigma_{ij}^{(\alpha)} = 0$$

Strain tensor

$$E^{(\alpha)} = \frac{1}{2} e_{ij}^{(\alpha)} \sigma_{ij}^{(\alpha)} \quad e_{ij}^{(\alpha)} = \frac{1}{2} (\partial_j u_{\alpha,i} + \partial_i u_{\alpha,j})$$

$$\sigma_{ij}^{(\alpha)} = \frac{E}{1+\nu} [e_{ij}^{(\alpha)} + \frac{\nu}{1-2\nu} e_{ll}^{(\alpha)} \delta_{ij}] \quad \alpha = (\text{Si soit Ge})$$

Boundary conditions :Stress and strain are continuous at the Si/Ge interface, no dislocations.

$$\mathbf{u}_s = \tilde{\mathbf{u}}_f \text{ and } \boldsymbol{\sigma}_s \cdot \hat{\mathbf{z}} = \boldsymbol{\sigma}_f \cdot \hat{\mathbf{z}} \quad \text{at } z = 0$$

$$\boldsymbol{\sigma}_f \cdot \hat{\mathbf{n}} = 0 \quad \text{at } z = h(x, y, t) \quad \text{No stress at the free boundary (non-linear geometrical conditions)}$$

Linear analysis :

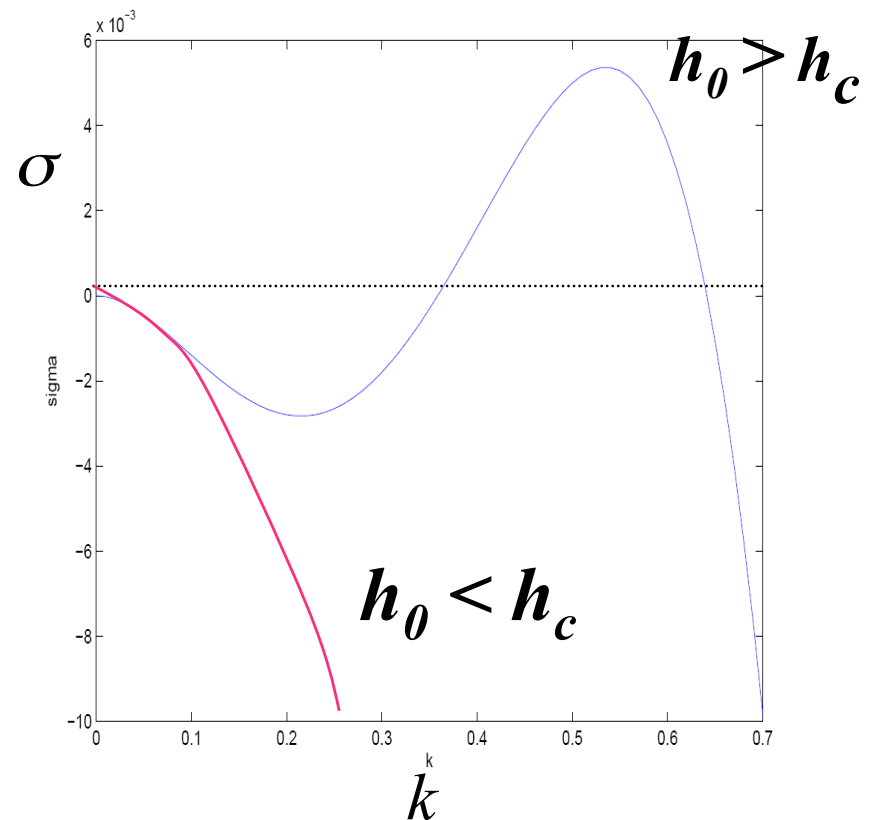
$$h(x, y, t) = h_0 + \delta h e^{i\mathbf{k}\cdot\mathbf{r} + \sigma t}$$

$$k = |\mathbf{k}|$$

$$\sigma = -c_w k^2 + \left(\frac{\delta a}{a}\right)^2 k^3 - k^4$$

$$\gamma(h) = \gamma [1 + c_w \exp(-h/\delta)]$$

Flat film stable
for $h_0 < h_c$



Small slope equation

$$\frac{\partial h}{\partial t} = \frac{\partial^2}{\partial x^2} \left\{ - \left[1 + c_w f\left(\frac{h}{\delta}\right) \right] h_{xx} + \frac{c_w f'(h/\delta)}{\delta \sqrt{1 + h_x^2}} - \omega_1 \mathcal{H}(h_x) \right. \\ \left. + \omega_2 (2hh_{xx} + h_x^2) + \omega_2^* (2\mathcal{H}\{[h\mathcal{H}(h_x)]_x\} + [\mathcal{H}(h_x)]^2) \right\},$$

**Singular
term**

**Nonlinear nonlocal terms which prevents the
singularity.**

$$\gamma(h) = \gamma_f [1 + c_w f(h/\delta)]$$

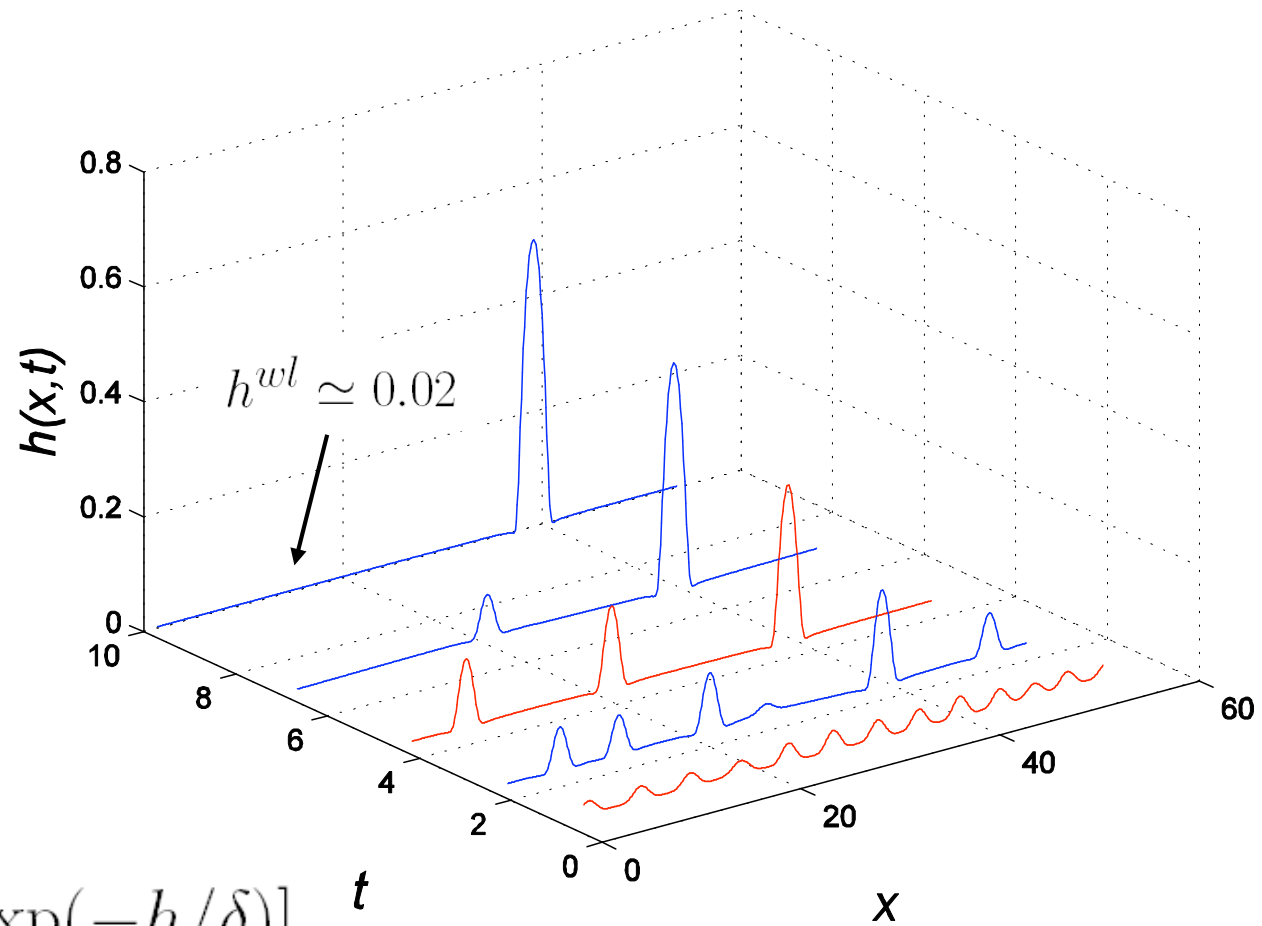
$$f(\xi) = \exp(-\xi)$$

f is the wetting potential

$$\mathcal{H}[h_x] = \mathcal{F}^{-1}\{|k|\mathcal{F}[h]\}$$

**H is the Hilbert transform,
multiplication by k in Fourier Space**

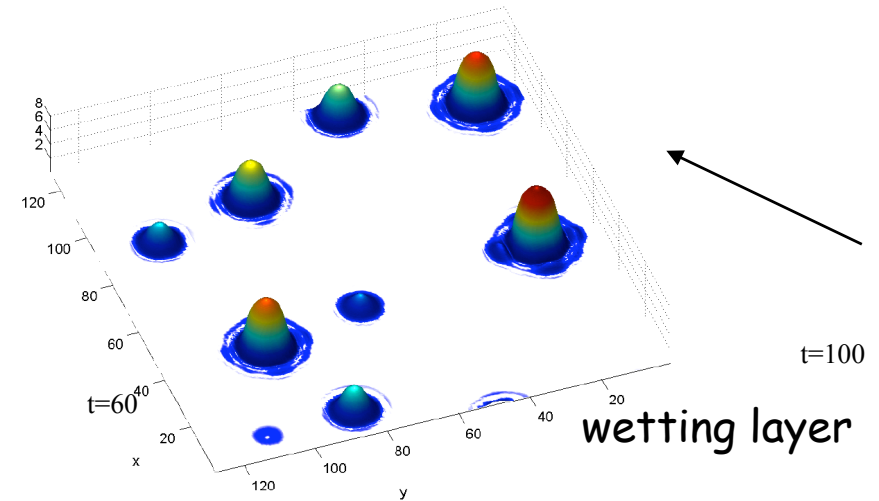
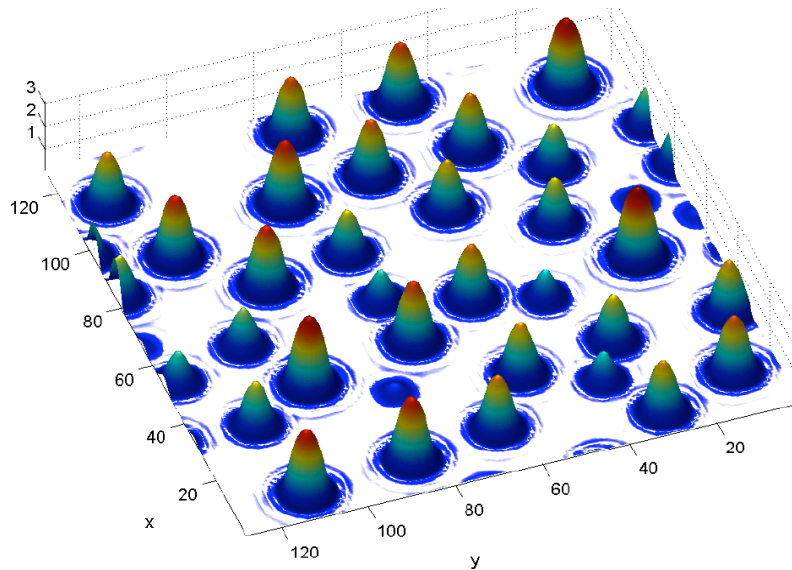
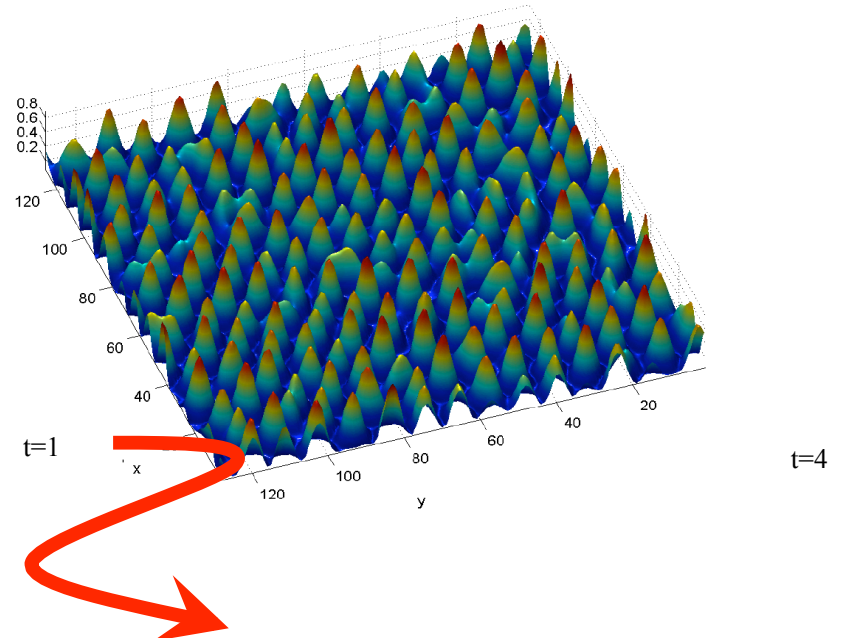
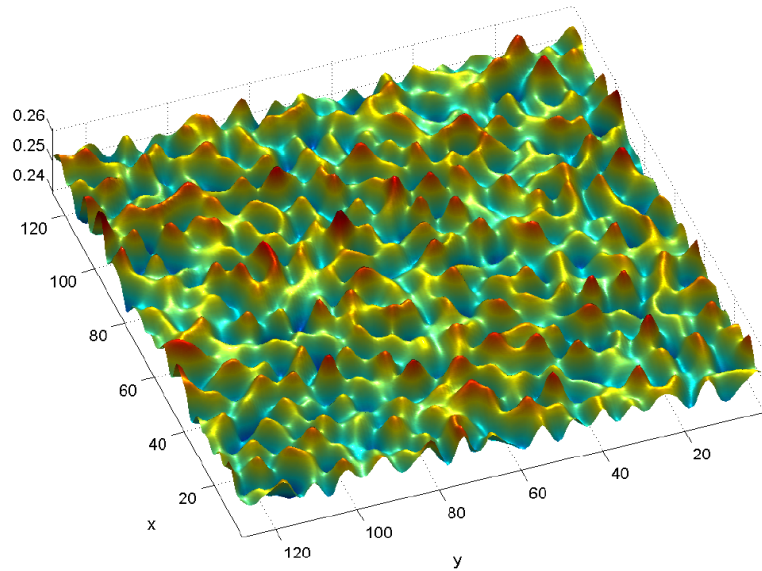
NO singularity when BOTH wetting (small, not diverging)
& non-linear non-local effects are considered



$$\gamma(h) = \gamma [1 + c_w \exp(-h/\delta)]$$

$$c_w = 0.1$$

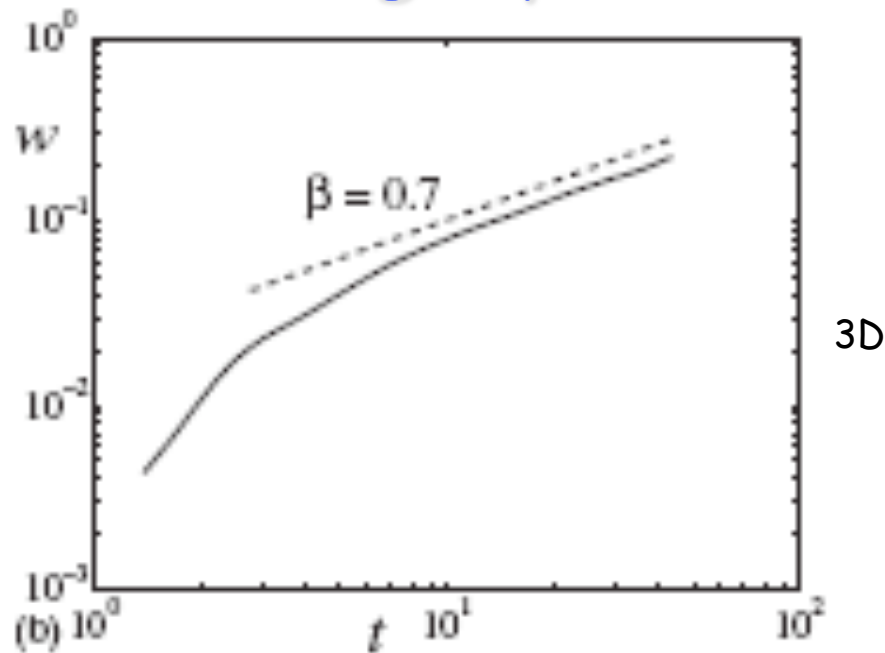
Numerical Simulations using Spectral Methods



Non-interrupted coarsening

Large islands grow at the expense of the small ones

Coarsening dynamics: numerical simulations

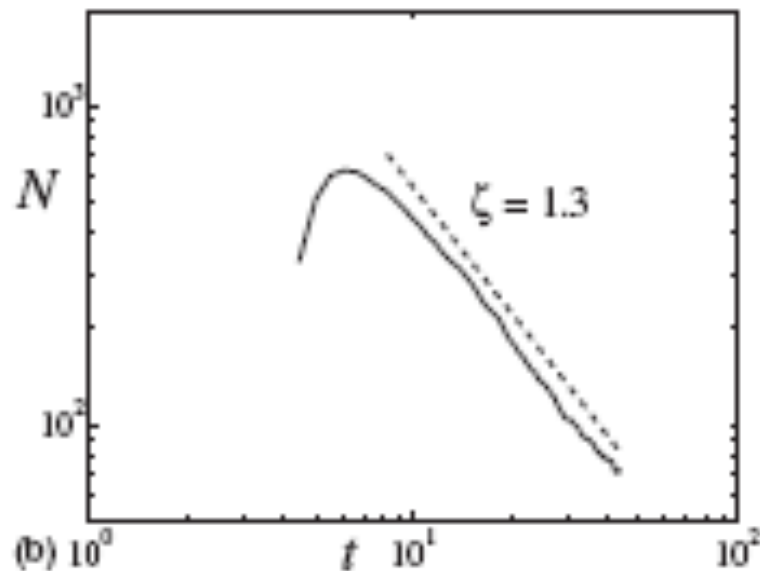


1. roughness

$$w(t) = [\langle h^2 \rangle - \langle h \rangle^2]^{1/2}$$

$$w(t) \sim t^\beta$$

JNA, Frisch, Verga, PRB 07



2. Number of islands

$$N(t) \sim 1/t^\zeta$$

Dynamics of the coarsening

Some discussion about the coarsening exponent:

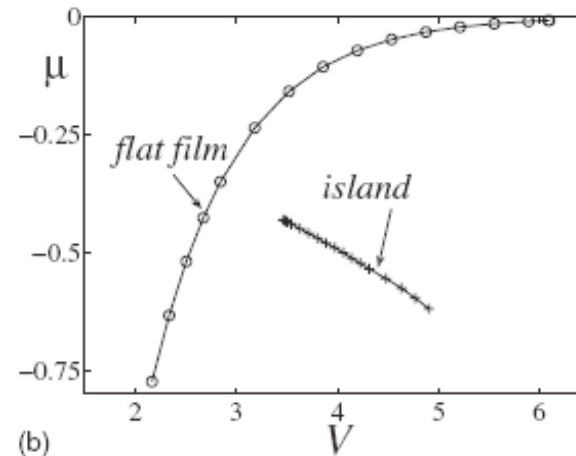
$$w(t) \sim t^\beta$$

$$N(t) \sim 1/t^\zeta$$

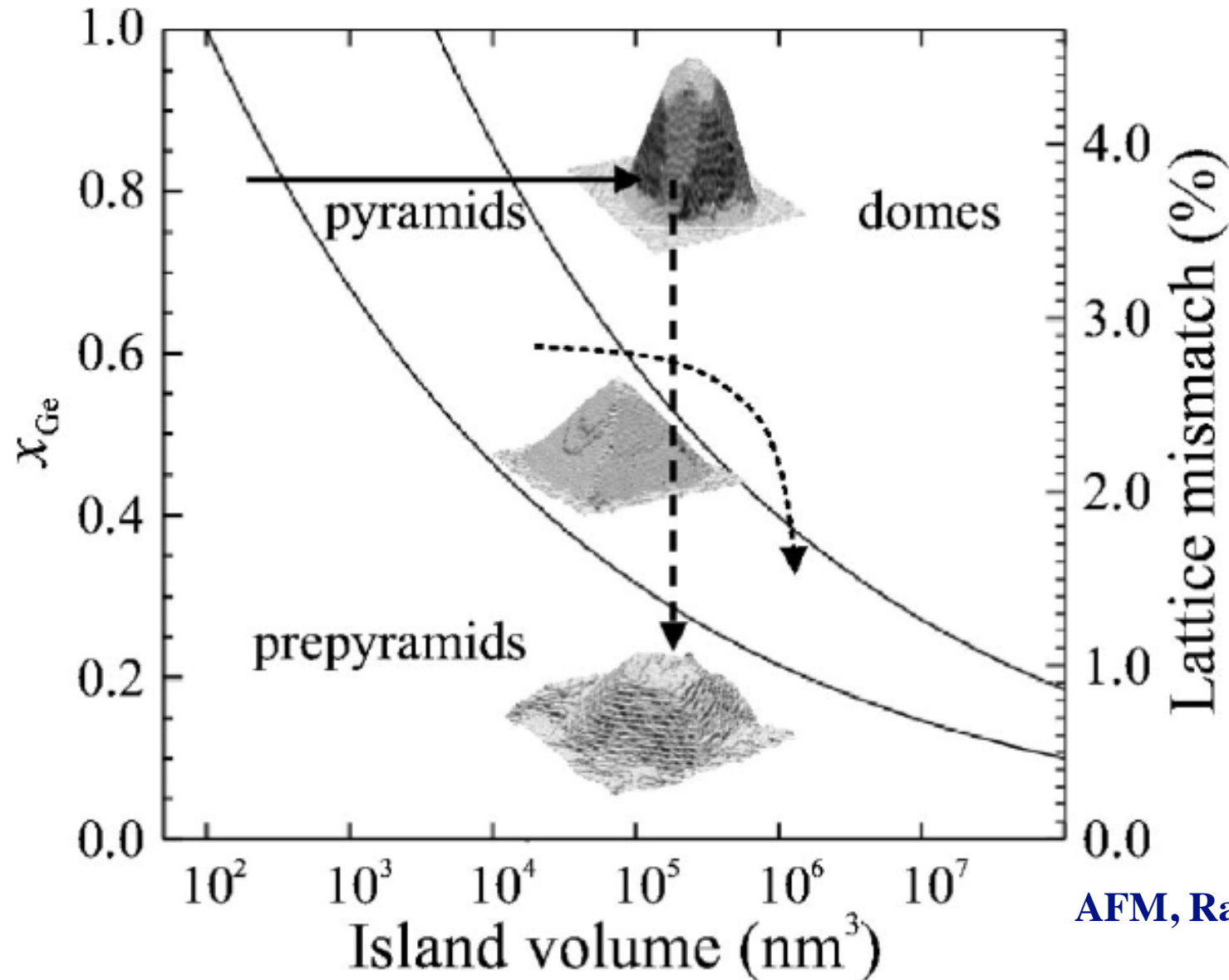
	Levine, Golovin, Davis, Voorhees PRB 07	Pang, Huang PRB 06	Aqua, Frisch, Verga PRB PRB 07
β	2.88	0 saturation	0.7
ζ	2.9	N/A	1.3

Annealing
Hypothesis :

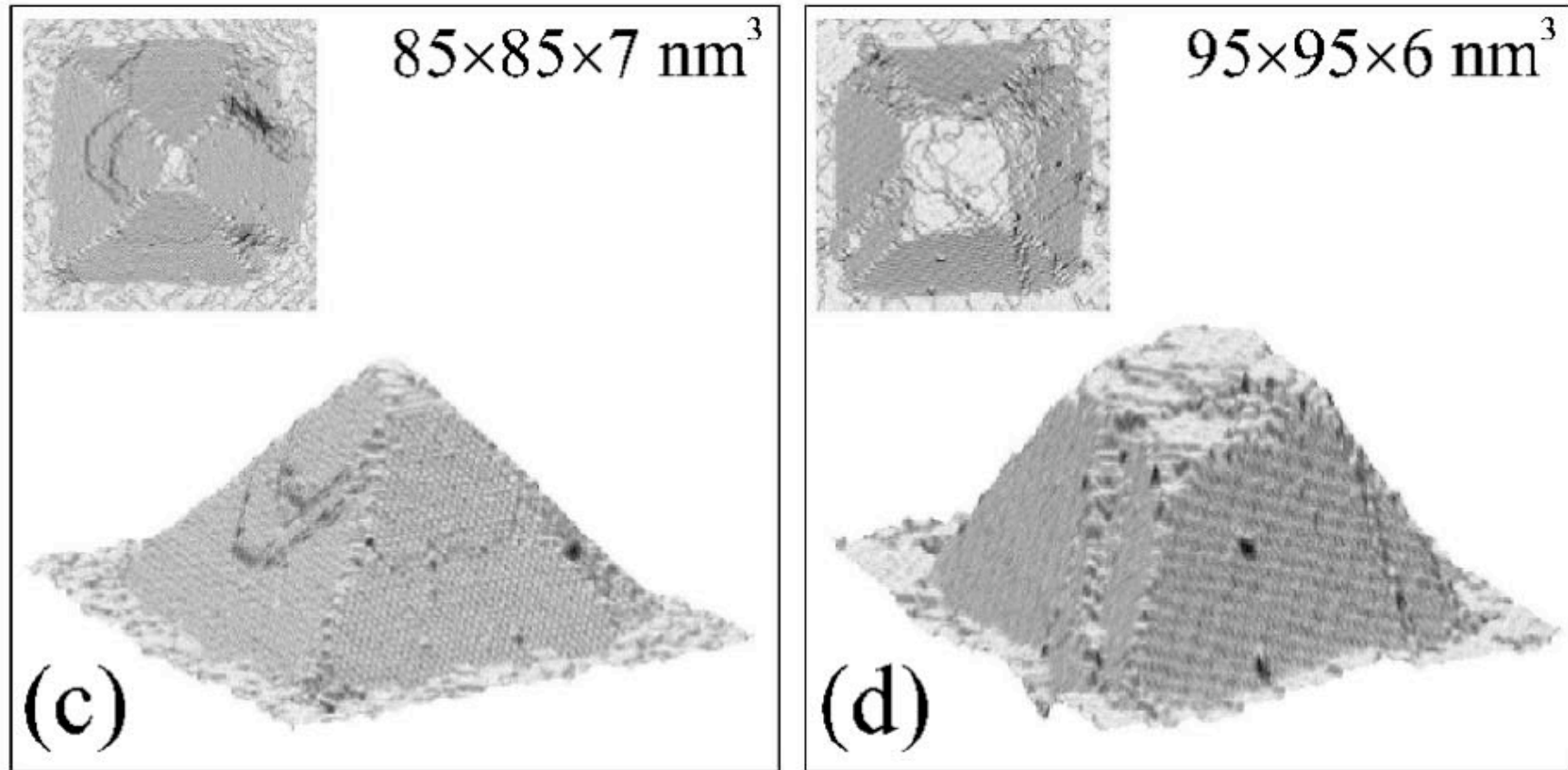
No facetting :
No alloying :



Silicon/germanium island are faceted



Silicon Germanium island



**AFM, RMP 04, Rastelli,
the (105) is apparent**

Surface energy anisotropy

$$\mathcal{F}^s = \int \gamma(h, \mathbf{n}) \sqrt{1 + |\nabla h|^2} dr$$

$$\mathcal{F}^{el} = \int_{z < h(\mathbf{r})} \mathcal{E}^{el}(\mathbf{r}, z) dr dz.$$

\mathbf{n} is normal to the surface

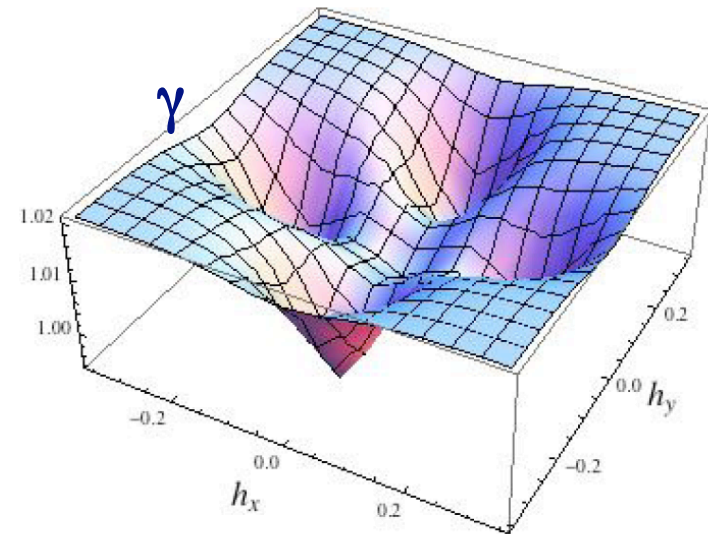
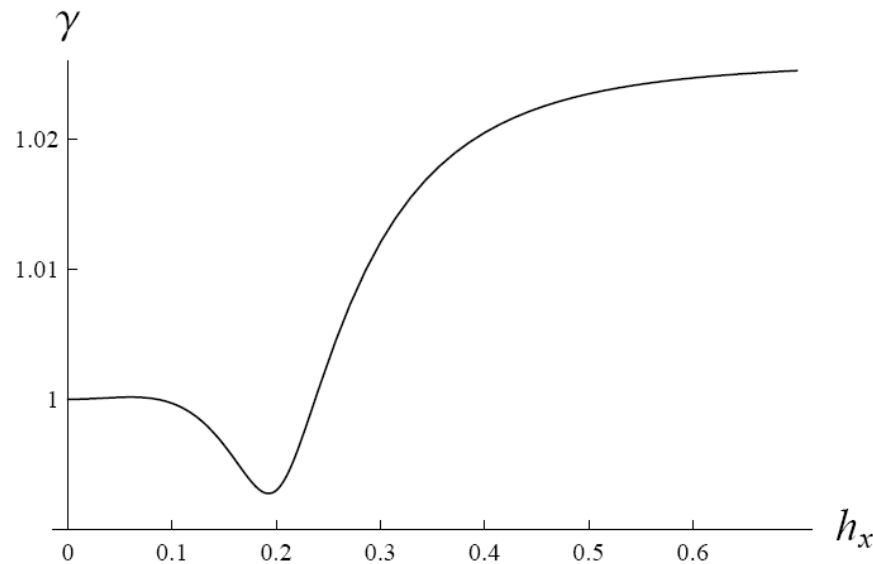
$$F = F^s + F^{el}$$

$$\mu = \delta \mathcal{F} / \delta h$$

The surface energy depends on the orientation and also on the elastic-strain.

We neglect the second effect but we take a minimum for the (105) orientation.

Effect of the anisotropy of surface energy (Gamma Plot)

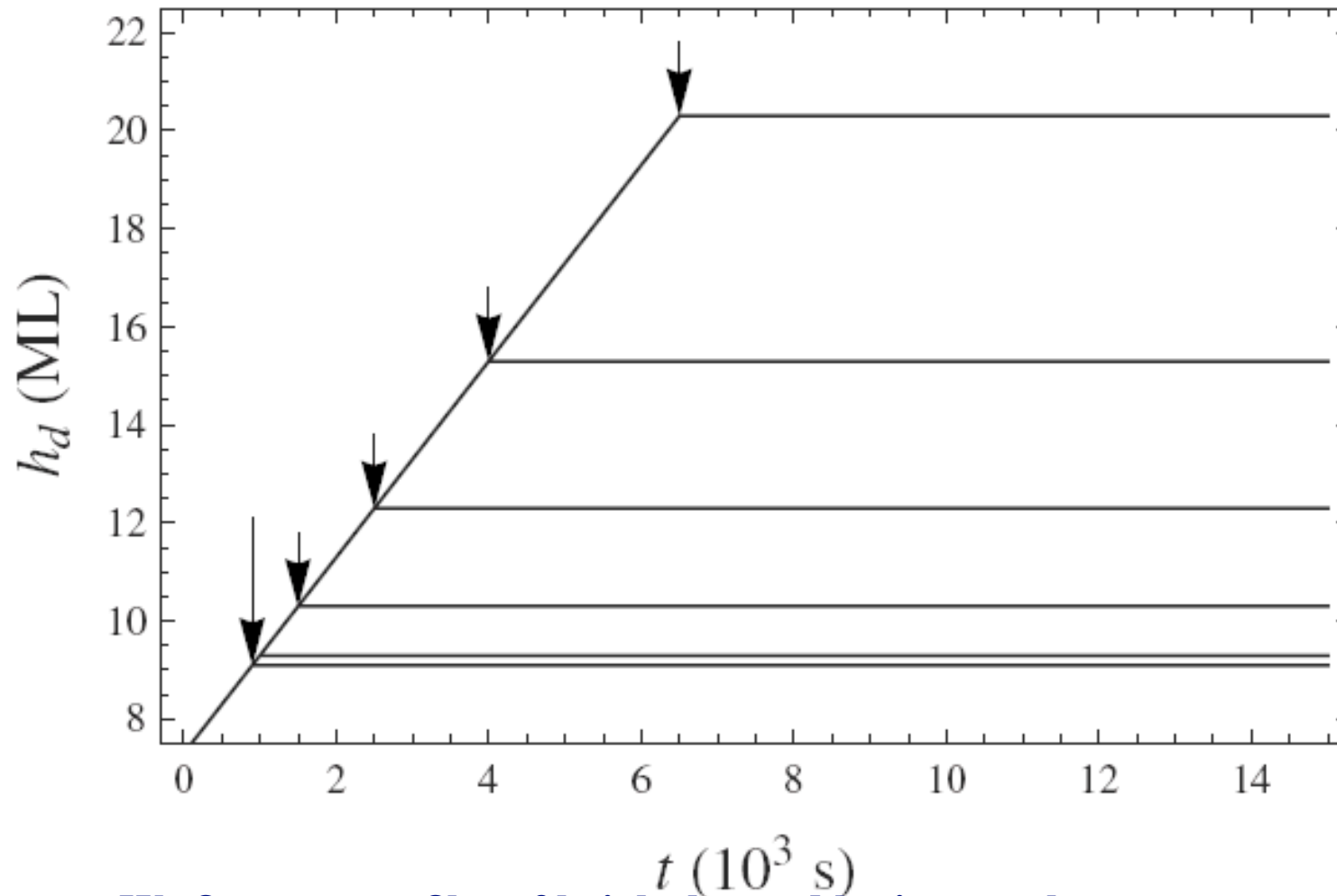


$$\gamma(h, \mathbf{n}) = \gamma_f [1 + \gamma_n(\mathbf{n}) + \gamma_h(h)]$$

In a crystalline solid, the surface energy depends on the orientation $\gamma(\mathbf{n})$ and also on the elastic-strain.

Y. W. Zhang, Phys Rev B, 61, 2000

Numerical Protocol



We first grow a film of height h_d and let it anneal.

The deposited height h_d is the relevant parameter.

Evolution of the island density

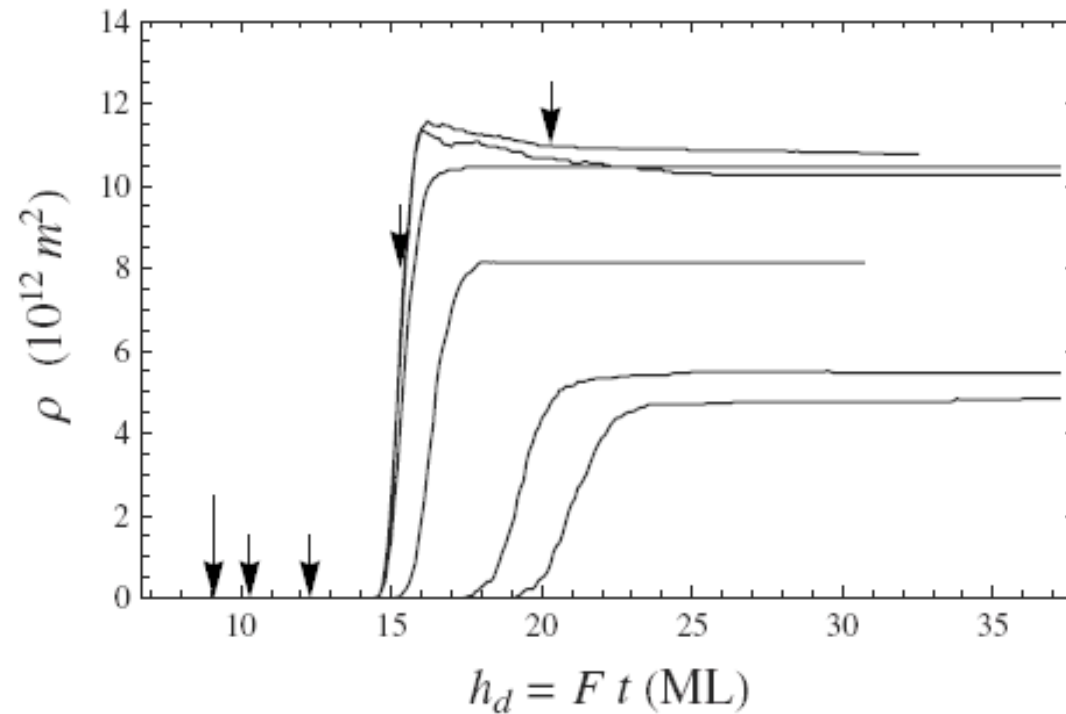
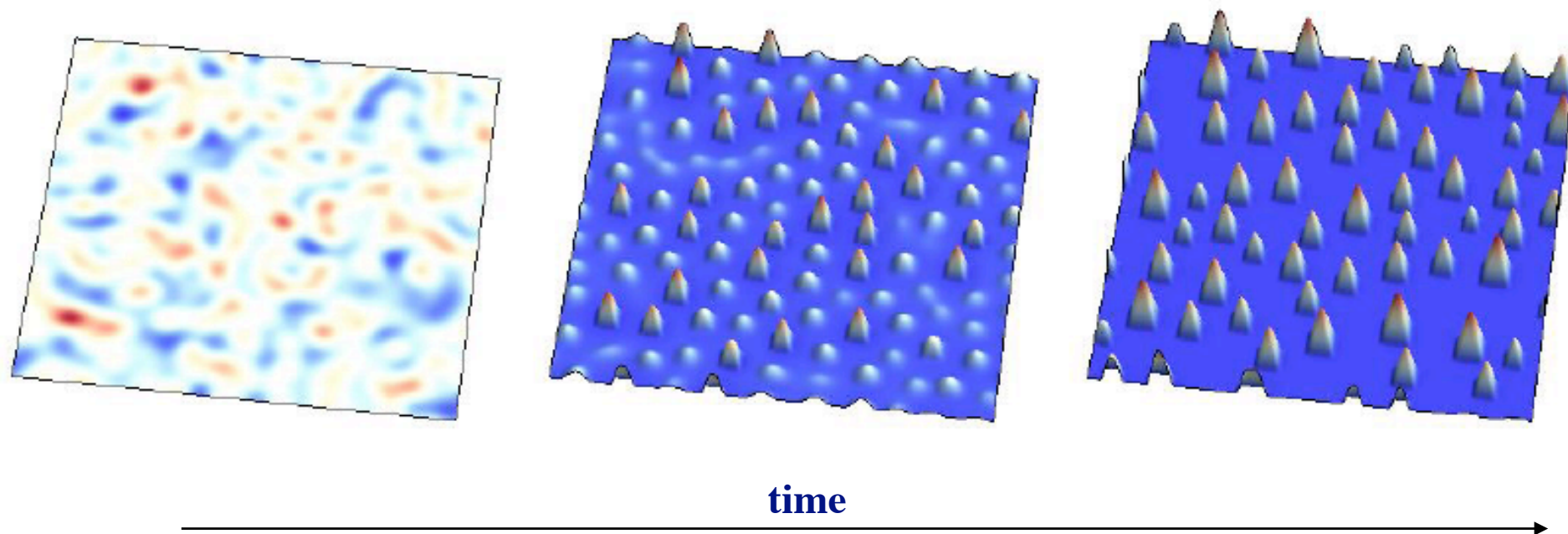


FIG. 8. Numerical results of Eq. (32). Evolution of the island density versus time for, from bottom to top, the cases (a,b,c,d,e,f).

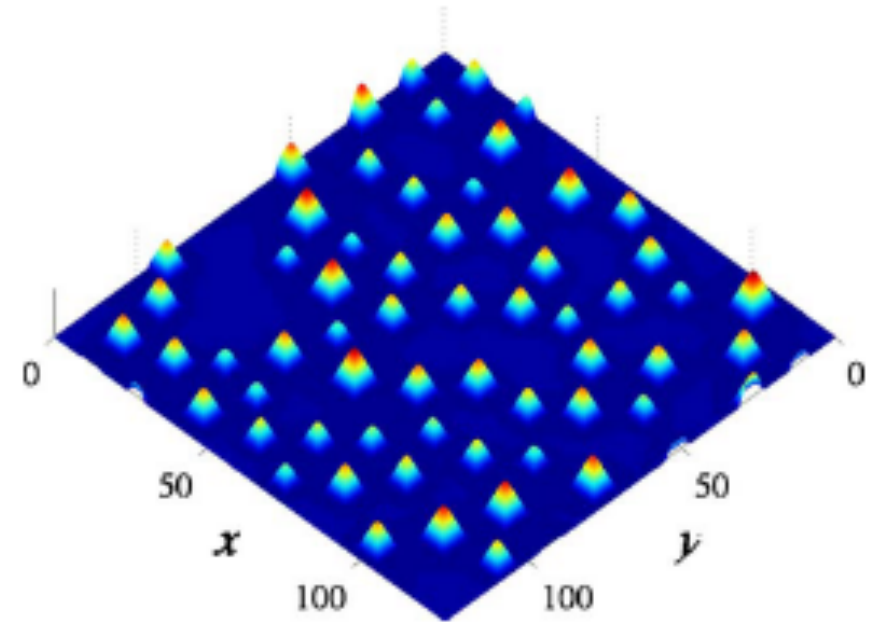
Time evolution



Top= 9 ML

$L=128 I_0$

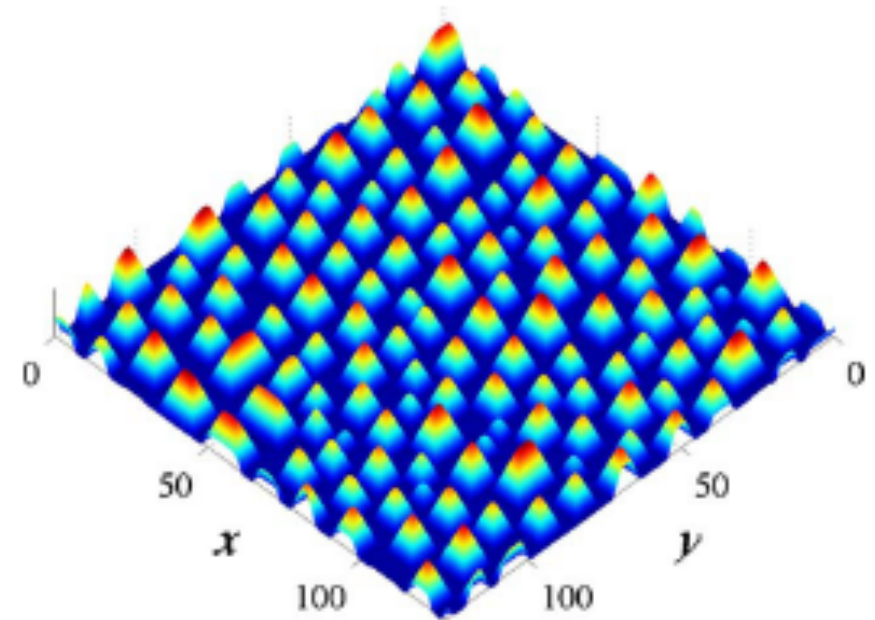
$I_0=27 \text{ nm}$



Bottom = 20.2 ML

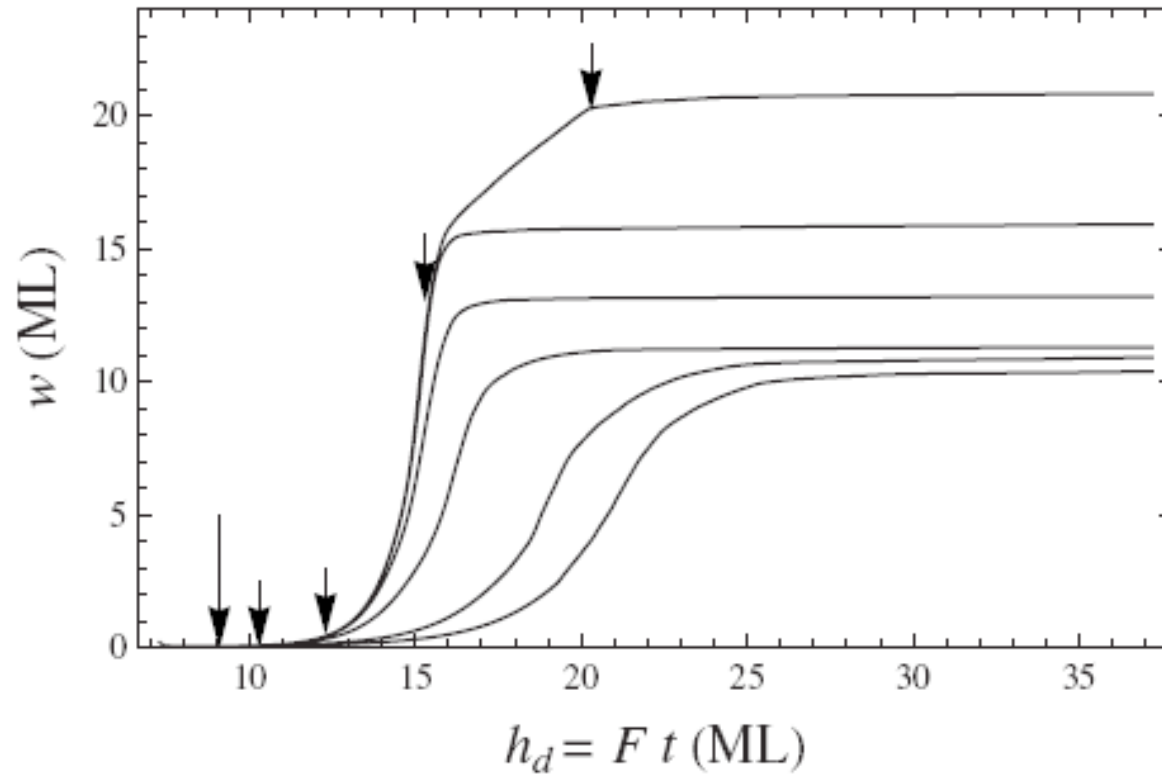
Anneal time is 300

Minutes



Simulations

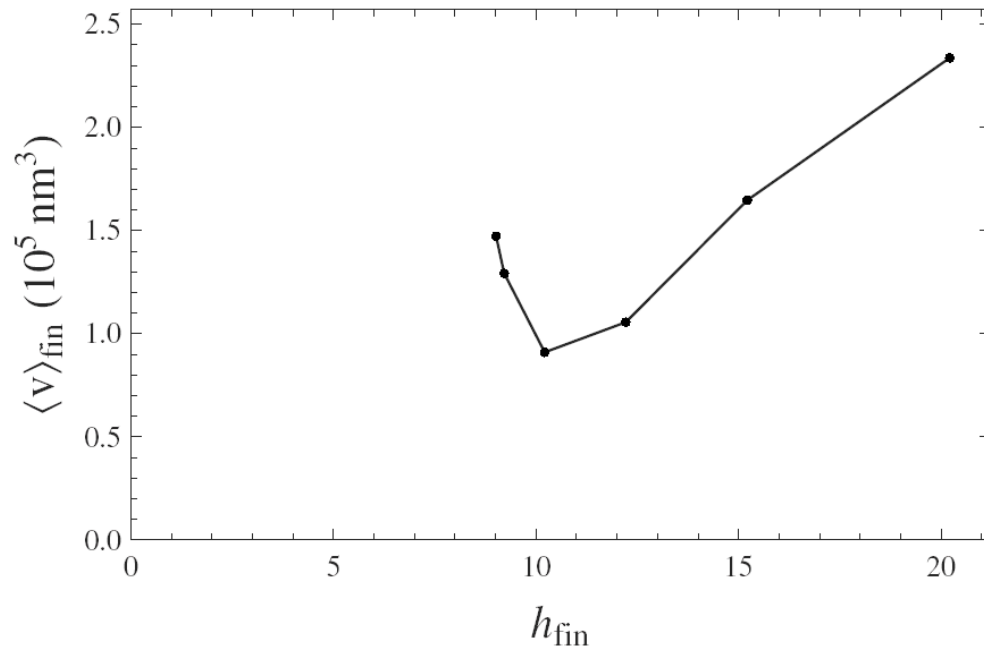
Evolution of the roughness



Coarsening is interrupted

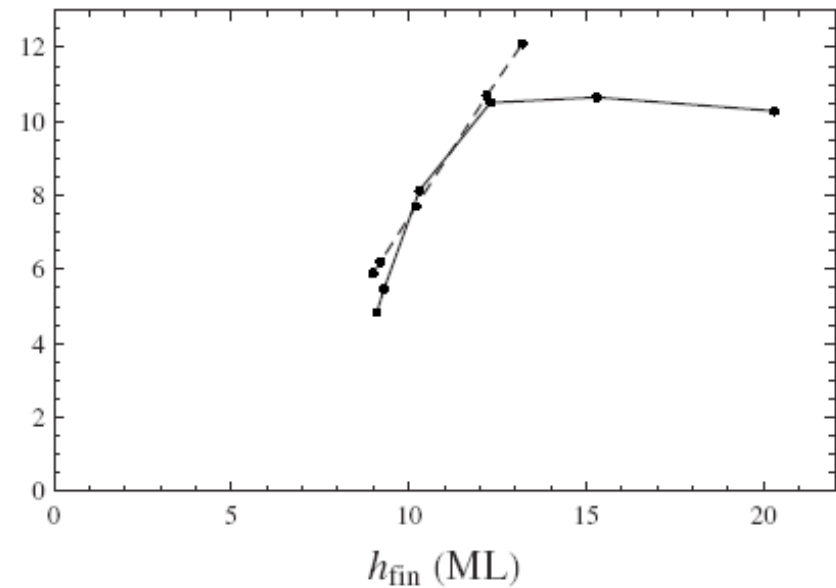
Dots density and size can be controlled: coarsening is interrupted

Island Volume



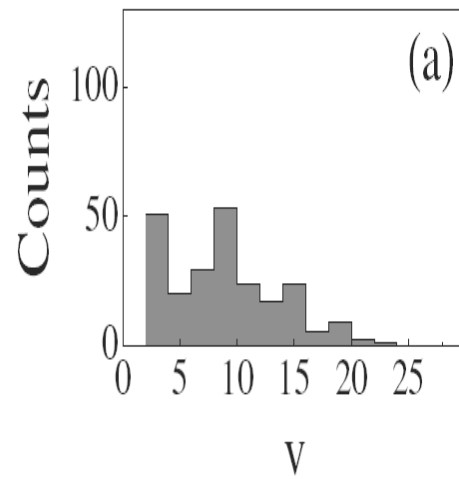
Numerical simulation

density

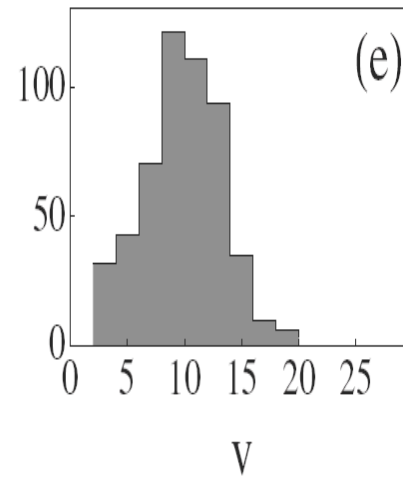


We can vary the dots density as a function of the deposited height

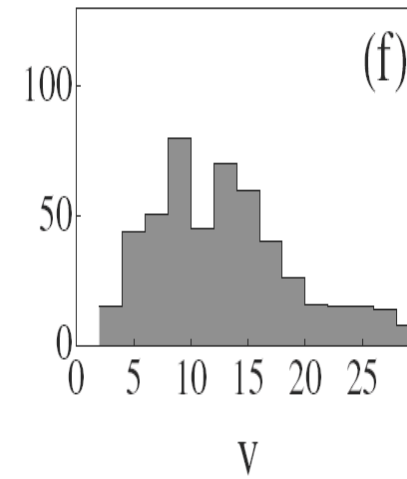
Distribution of island sizes



9ML



15 ML



20 ML

Dispersion of island size distribution: r.m.s.

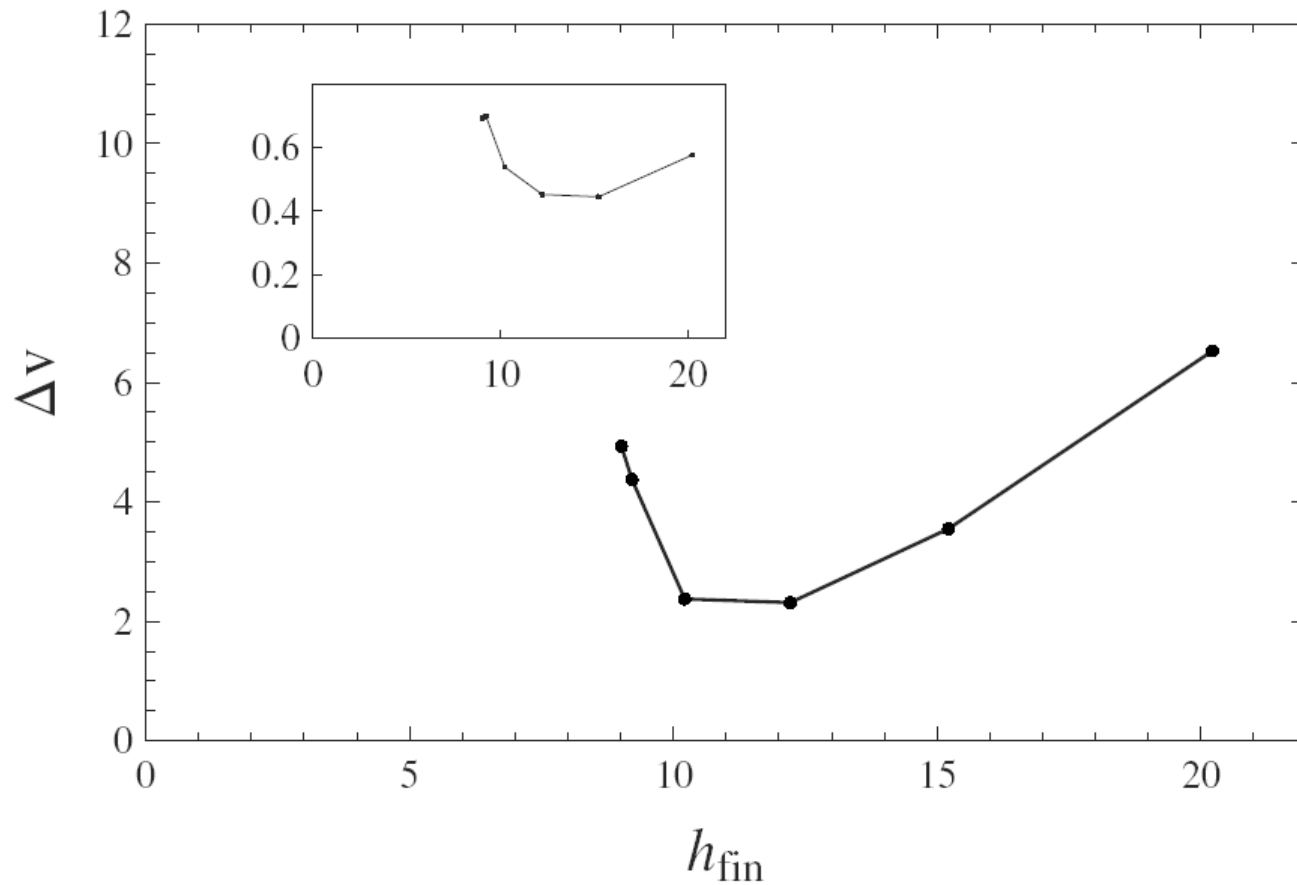
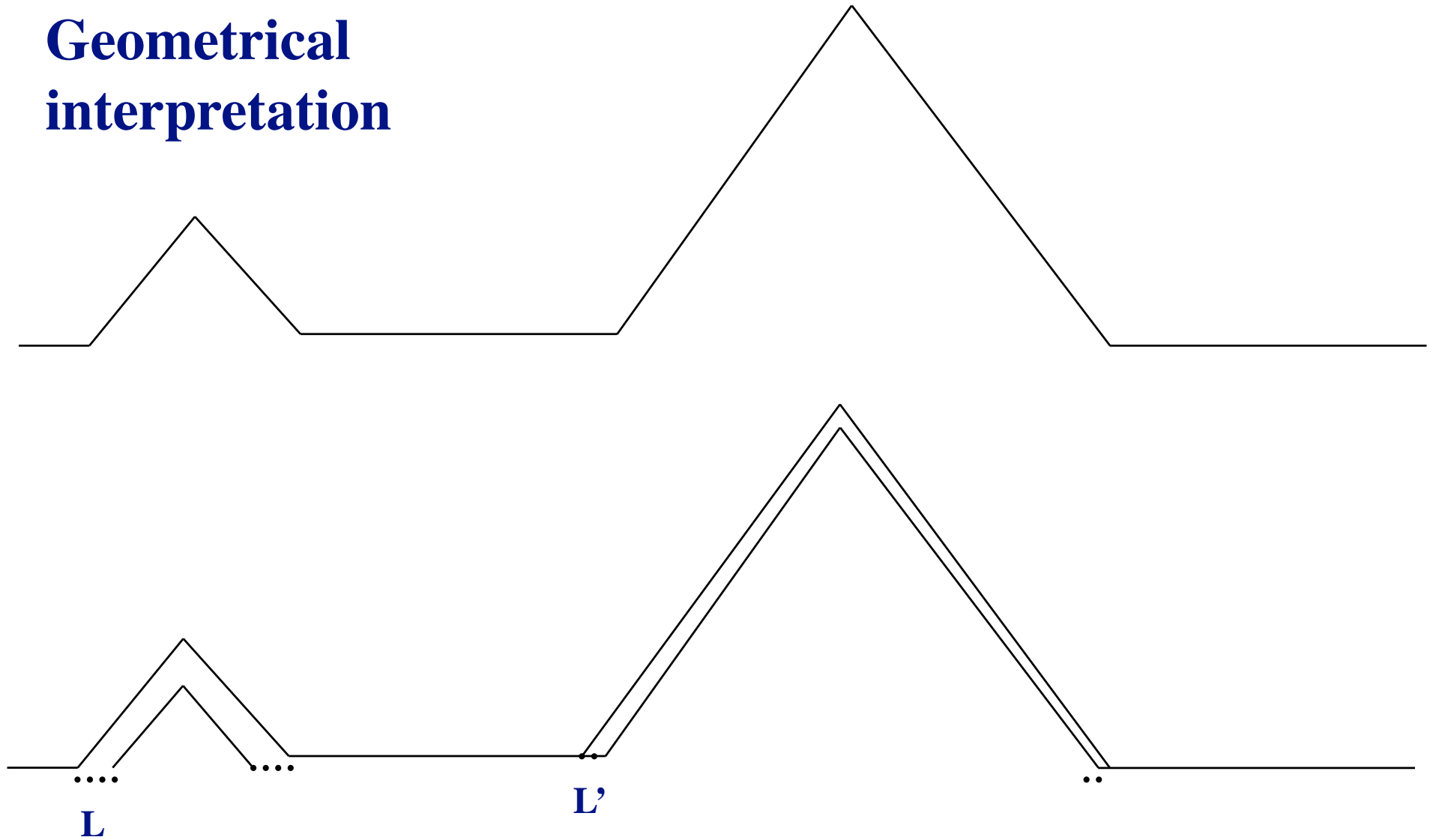


FIG. 14. Standard deviation Δv of the island size distribution as function of the amount of matter and (inset) relative width $\Delta v / \langle v \rangle$.

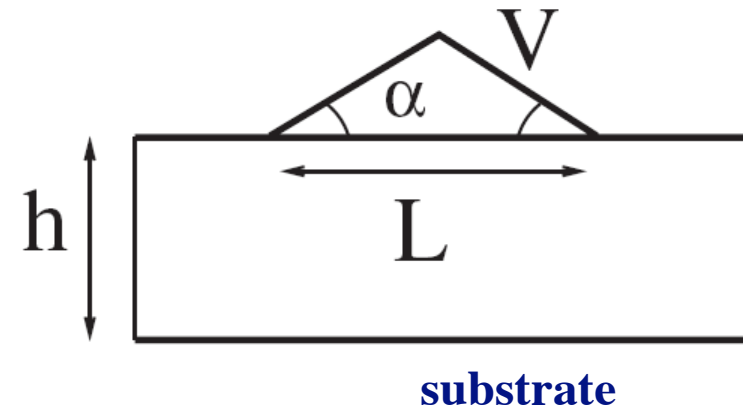
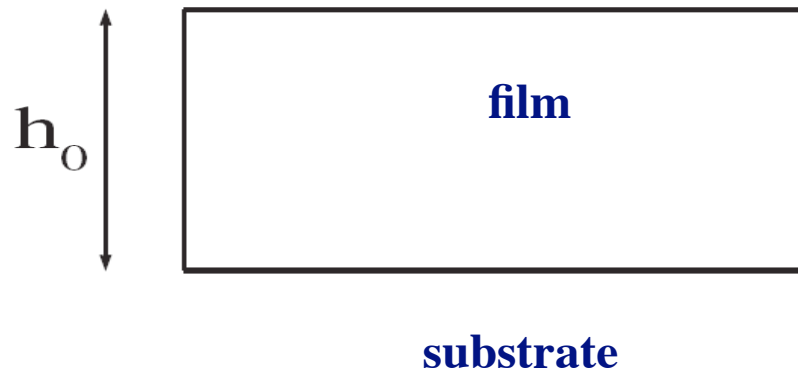
Geometrical interpretation



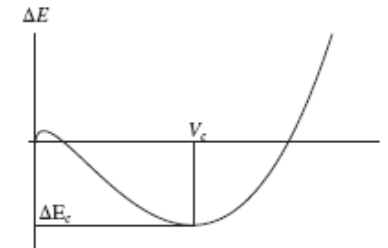
Aqua-Frisch,
2010, Phys Rev B
76

$L > L'$, the wetting energy increases, but the surface energy decrease and the elastic energy remains constant.

Energetic model



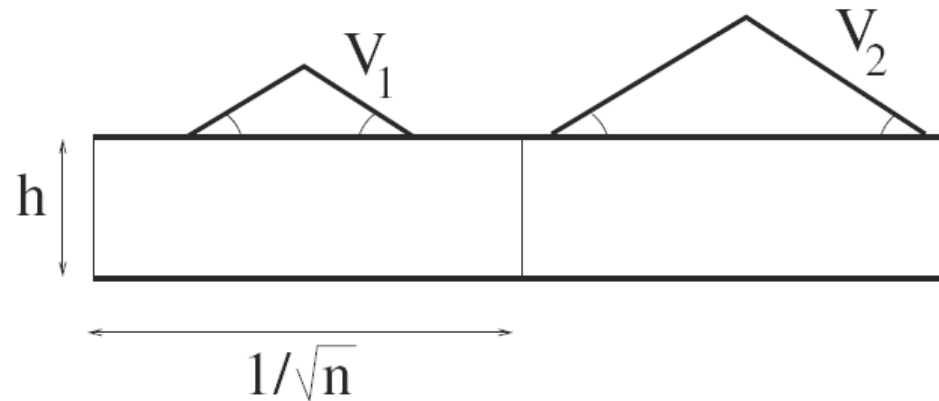
$$h = h_0 - nV.$$



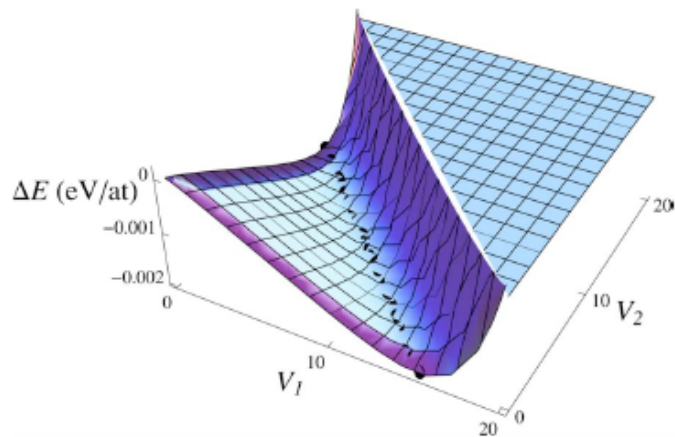
$$\Delta E = \gamma_f L^2 / \cos \alpha - L^2 \gamma(h_0) + (1/n - L^2) [\gamma(h) - \gamma(h_0)] - \lambda_e V.$$

⁴³L. G. Wang, P. Kratzer, M. Scheffler, and N. Moll, *Phys. Rev. Lett.* **82**, 4042 (1999).

Two-island model



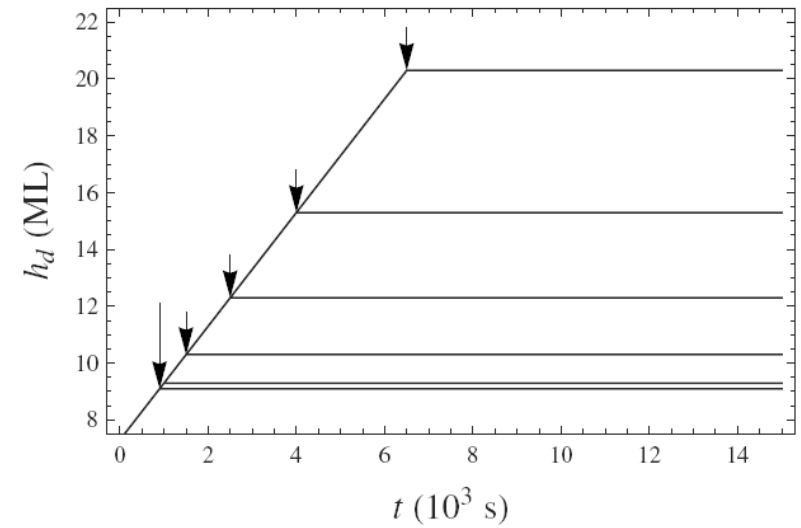
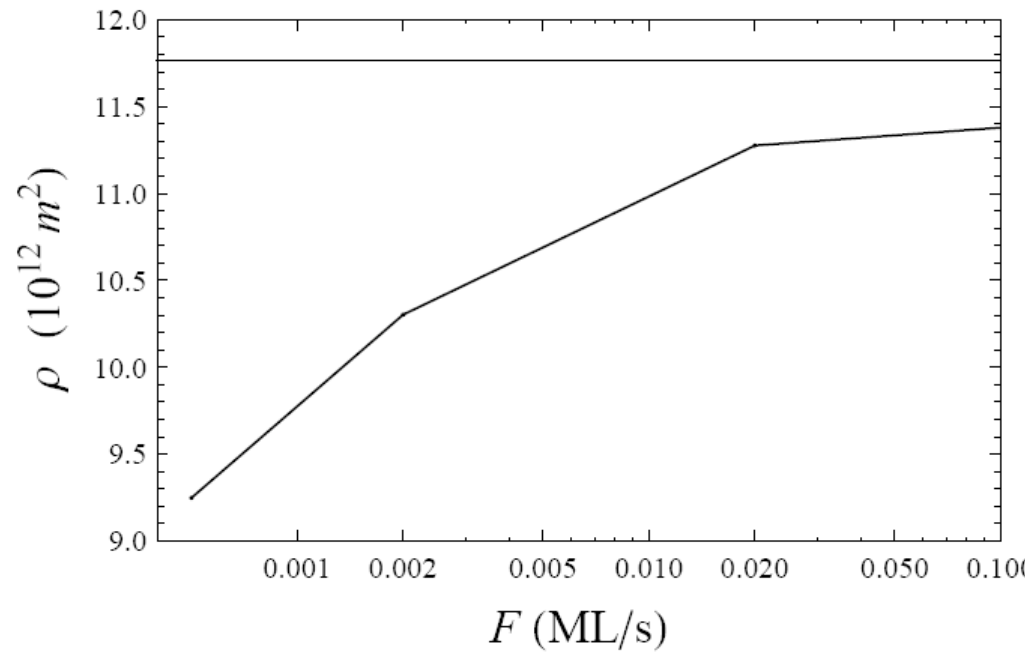
**Two free parameters are: the height of the wetting layer,
and the surface density of pyramids**



$V_1 = V_2$ is a valley with a very small slope.

J.-N. Aqua, T. Frisch, PRB, 82, 085322, 2010

Effect of the flux



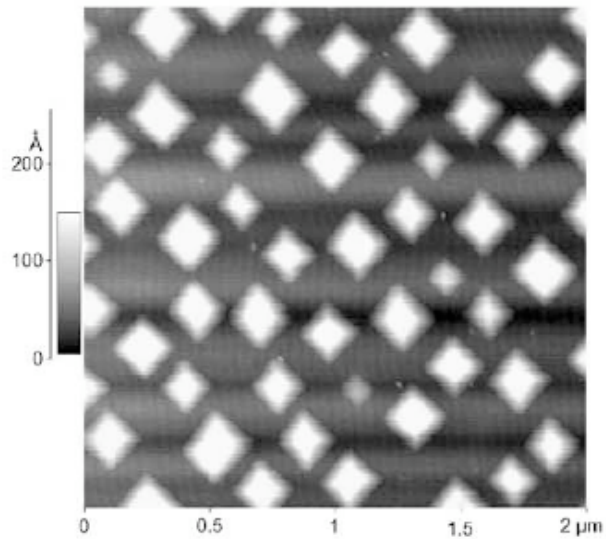
The flux does not really affect the density of island for $h_d = 11.7$

Experimental results

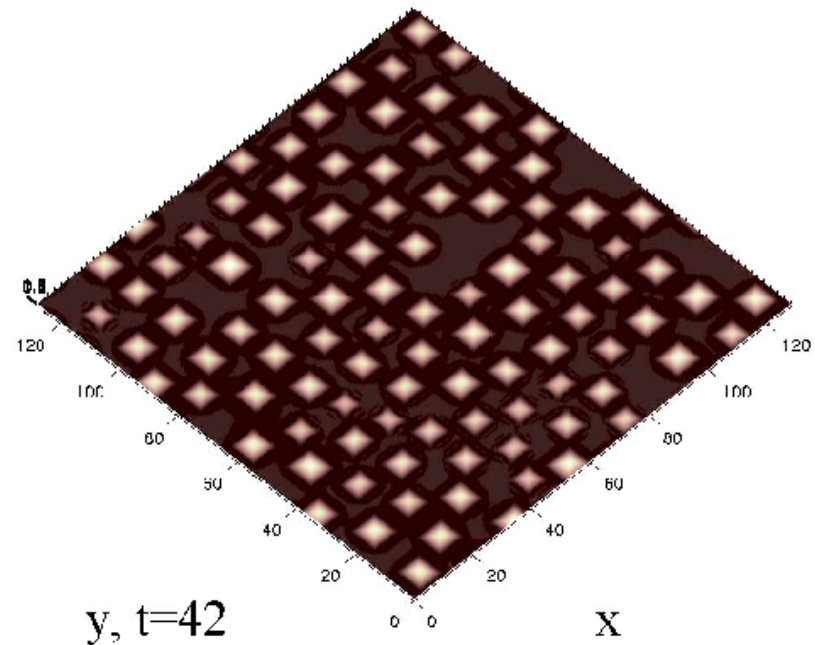
- $\text{Si}_{0.7}\text{Ge}_{0.3}$ annealed at 550 celcius for 54 hours for different deposited height.

**MBE group of Isabelle
Berbezier**

Interrupted coarsening is also observed experimentally



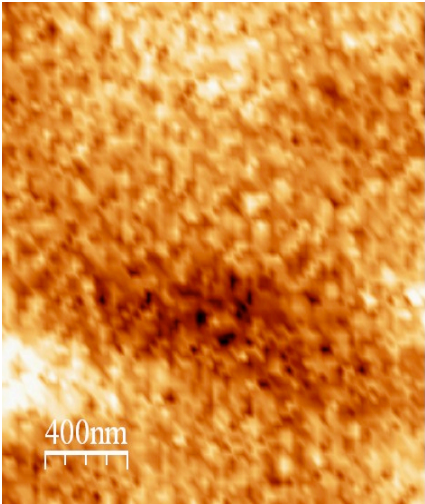
**Experiments, I.
Berbezier, 2002, J.
Phys Cond
Matters, SiGe/Si
AFM**



Numerical simulations

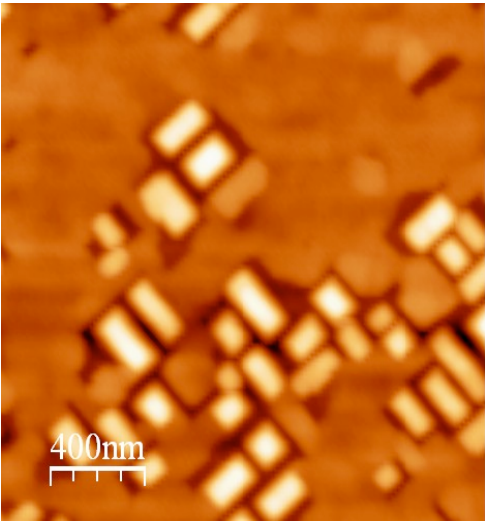
Experiments

Si_{0.70}Ge_{0.30} 550°C

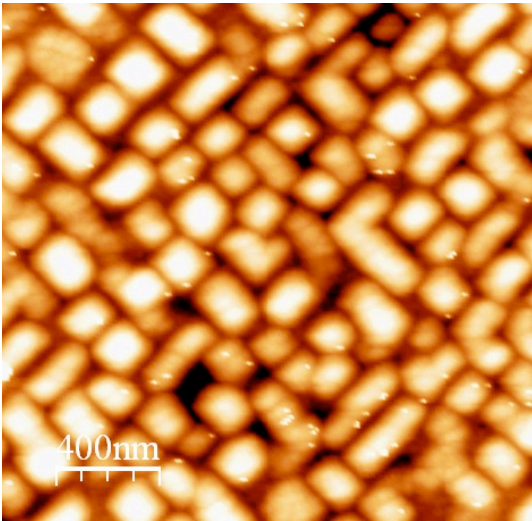


as grown

15.8 Monolayers



18 Hours annealing



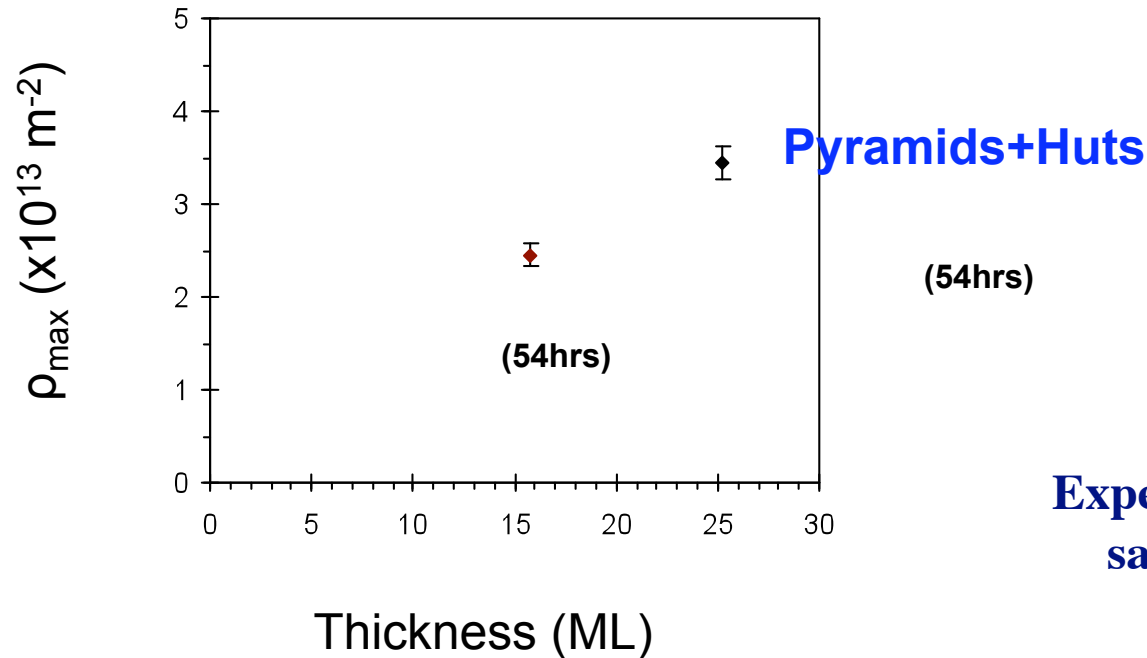
54 hours annealing

Time



Si_{0.70}Ge_{0.30} (550°C)

ρ_{\max} as function of the amount of matter



Experiments density falls with the same order of magnitude as the theory but a more detailed comparison is needed:

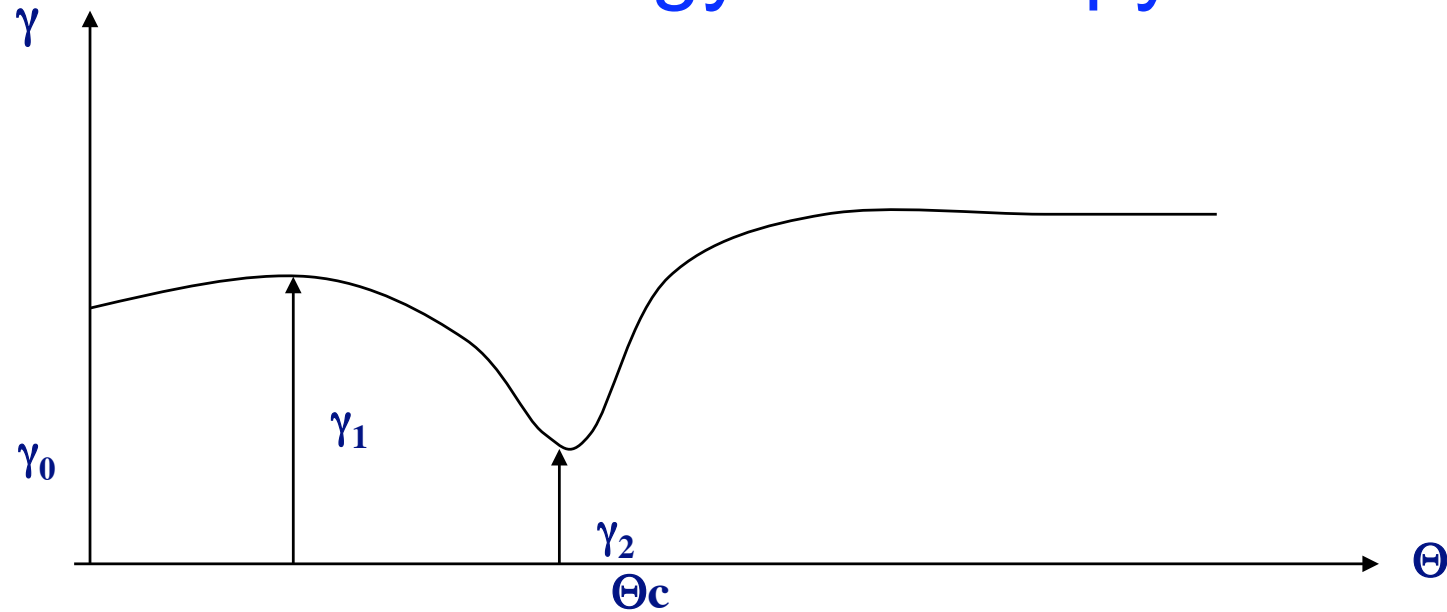
In particular, we are doing Ab_Initio calculation to extract the value of the diffusion coefficient (V. Oison)

1ML SiGe30% = 3.169A

Conclusion

- The elastic instability has a rich nonlinear regime
- We derived a fast methods for Stransky-Krastanov growth modeling in the instability regime
- Coarsening is interrupted due to the interplay between anisotropy of surface energy and the wetting effect.
- We may control the dots size on Si/Ge by varying the deposited height and the strain

How sensitive is the dynamics on the effect of surface energy anisotropy ?



Question: For which values of γ_2/γ_0 the dynamics changes from non-interrupted coarsening to interrupted coarsening?

Is the sharpness at Θ_c is important

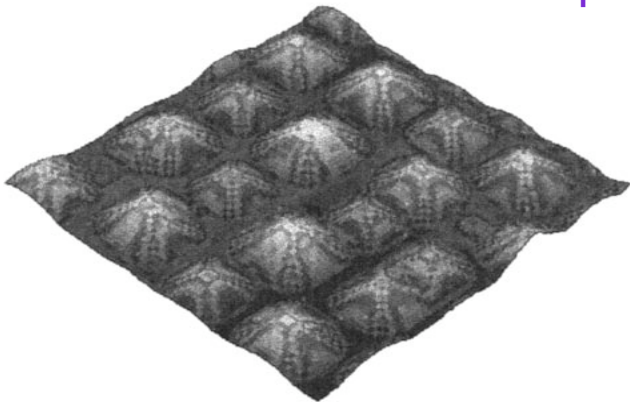
Close the instability threshold, it can be possible to compute a bifurcated solution and to verify the existence of periodic solutions (Landau expansion with anisotropy). One ingredient is period-doubling or tripling

Spencer, Voorhees and Tersoff, 2001, Tersoff, APL, 2003 Tu and Tersoff, PRL 2004, Tu and Tersoff, PRL 2007

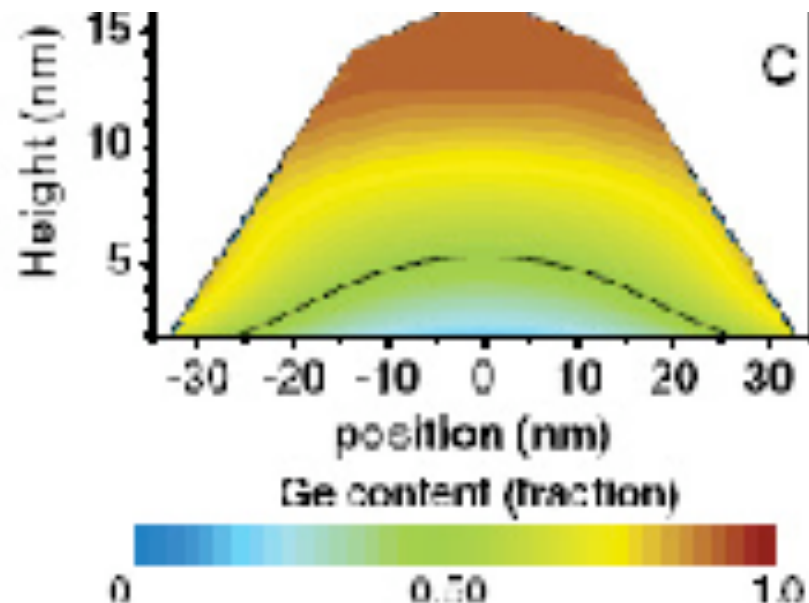
Perspectives on alloying.

- Alloying phenomena during Si/Ge growth, effect of surface segregation effect,
- Application are on the III/V semiconductor.
- Nonlinear coupling between the compositional and the morphological instabilities. The alloys concentration is spatially inhomogeneous and it has an impact on the opto-electronic properties.
- Electron Phase microscopy analysis of alloys composition (P. Donnadieu, SIMAP, Grenoble, and I. Berbezier IM2NP)

What is the island composition ?



Floro **et al**, PRB
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Medeiros-Ribeiro, PRL 2008, ESRF, Synchrotron X

Collaborators: Adrien Gouye, Isabelle Berbezier, Antoine Ronda, Alberto Verga.

Relevant Publications :

J.-N Aqua, T. Frisch and A. Verga, Phys Rev B, 2007

J.-N Aqua, T. Frisch, Phys Rev B, 2008, (Elastic Kinetic Monte-Carlo, island size distributions)

J.-N Aqua, T. Frisch and A. Verga, Phys Rev E 2010 (Flux effect)

J.-N Aqua, T. Frisch, Phys Rev B (2010)

Graduate Student: Xian Bin Xue, and Philippe Gaillard



**Si-Ge growth of FIB
patterned substrate**



**Compositional and
morphological coupling**